

MOS INTEGRATED CIRCUIT

μ PD78F0034B, 78F0034BY, 78F0034B(A), 78F0034BY(A)

8-BIT SINGLE-CHIP MICROCONTROLLERS

DESCRIPTION

The μ PD78F0034B is a member of the μ PD780034A Subseries in the 78K/0 Series, and is equivalent to the μ PD780034A (expanded-specification product) but with flash memory in place of internal ROM.

The μ PD78F0034BY is a member of the μ PD780034AY Subseries, featuring flash memory in place of the internal ROM of the μ PD780034AY.

The μ PD78F0034B(A) and 78F0034BY(A) are products to which a quality assurance program more stringent than that used for the μ PD78F0034B and 78F0034BY (standard models) is applied (NEC Electronics classifies these products as "special" quality grade models).

The μ PD78F0034B, 78F0034BY, 78F0034B(A), and 78F0034BY(A) incorporate flash memory, which can be programmed and erased while mounted on the board.

Detailed function descriptions are provided in the following user's manuals. Be sure to read them before designing.

 μ PD780024A, 780034A, 780024AY, 780034AY Subseries User's Manual: U14046E 78K/0 Series Instruction User's Manual: U12326E

FEATURES

Pin-compatible with mask ROM versions (except VPP pin)

Flash memory: 32 KB^{Note}
 Internal high-speed RAM: 1,024 bytes^{Note}

Supply voltage: VDD = 1.8 to 5.5 V

Note The flash memory and internal high-speed RAM capacities can be changed with the memory size switching register (IMS).

Remark For the differences between the flash memory and the mask ROM versions, refer to 4. DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY, AND MASK ROM VERSIONS.

The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.

Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.



ORDERING INFORMATION

Part Number	Package	Internal ROM
μPD78F0034BGB-8EU	64-pin plastic LQFP (10 x 10)	Flash memory
μPD78F0034BGC-8BS	64-pin plastic LQFP (14 x 14)	Flash memory
μ PD78F0034BGK-9ET	64-pin plastic TQFP (12 x 12)	Flash memory
μPD78F0034BF1-CN3	73-pin plastic FBGA (9 x 9)	Flash memory
μPD78F0034BGB(A)-8EU	64-pin plastic LQFP (10 x 10)	Flash memory
μ PD78F0034BGC(A)-8BS	64-pin plastic LQFP (14 x 14)	Flash memory
μ PD78F0034BGK(A)-9ET	64-pin plastic TQFP (12 x 12)	Flash memory
μ PD78F0034BYGB-8EU	64-pin plastic LQFP (10 x 10)	Flash memory
μ PD78F0034BYGC-8BS	64-pin plastic LQFP (14 x 14)	Flash memory
μ PD78F0034BYGK-9ET	64-pin plastic TQFP (12 x 12)	Flash memory
μ PD78F0034BYF1-CN3	73-pin plastic FBGA (9 x 9)	Flash memory
μ PD78F0034BYGB(A)-8EU	64-pin plastic LQFP (10 x 10)	Flash memory
μ PD78F0034BYGC(A)-8BS	64-pin plastic LQFP (14 x 14)	Flash memory
μ PD78F0034BYGK(A)-9ET	64-pin plastic TQFP (12 x 12)	Flash memory

QUALITY GRADE

Part Number	Package	Quality Grade
μPD78F0034BGB-8EU	64-pin plastic LQFP (10 x 10)	Standard
μPD78F0034BGC-8BS	64-pin plastic LQFP (14 x 14)	Standard
μ PD78F0034BGK-9ET	64-pin plastic TQFP (12 x 12)	Standard
μPD78F0034BF1-CN3	73-pin plastic FBGA (9 x 9)	Standard
μPD78F0034BGB(A)-8EU	64-pin plastic LQFP (10 x 10)	Special
μPD78F0034BGC(A)-8BS	64-pin plastic LQFP (14 x 14)	Special
μ PD78F0034BGK(A)-9ET	64-pin plastic TQFP (12 x 12)	Special
μPD78F0034BYGB-8EU	64-pin plastic LQFP (10 x 10)	Standard
μ PD78F0034BYGC-8BS	64-pin plastic LQFP (14 x 14)	Standard
μ PD78F0034BYGK-9ET	64-pin plastic TQFP (12 x 12)	Standard
μPD78F0034BYF1-CN3	73-pin plastic FBGA (9 x 9)	Standard
μ PD78F0034BYGB(A)-8EU	64-pin plastic LQFP (10 x 10)	Special
μ PD78F0034BYGC(A)-8BS	64-pin plastic LQFP (14 x 14)	Special
μ PD78F0034BYGK(A)-9ET	64-pin plastic TQFP (12 x 12)	Special

Please refer to "Quality Grades on NEC Semiconductor Devices" (Document No. C11531E) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

CORRESPONDENCE BETWEEN MASK ROM PRODUCTS AND FLASH MEMORY PRODUCTS

• μPD780024A, 780034A Subseries

Mask ROM Products	Flash Memory Products
Expanded-specification products of μ PD780021A, 780022A, 780023A, 780024A Expanded-specification products of μ PD780031A, 780032A, 780033A, 780034A	μPD78F0034B
Conventional products of μ PD780021A, 780022A, 780023A, 780024A Conventional products of μ PD780031A, 780032A, 780033A, 780034A	μPD78F0034A
Expanded-specification products of μ PD780021A(A), 780022A(A), 780023A(A), 780024A(A) Expanded-specification products of μ PD780031A(A), 780032A(A), 780033A(A), 780034A(A)	μPD78F0034B(A)
Conventional products of μ PD780021A(A), 780022A(A), 780023A(A), 780024A(A) Conventional products of μ PD780031A(A), 780032A(A), 780033A(A), 780034A(A)	μPD78F0034B(A)

Caution The μ PD78F0034B(A) and conventional products of the μ PD780021A(A), 780022A(A), 780023A(A), 780024A(A) and μ PD780031A(A), 780032A(A), 780033A(A), and 780034A(A) differ in the operating frequency ratings. When using the mask ROM versions in place of the flash memory versions, take note of the power supply voltage and operating frequency used.

- Remarks 1. The μ PD78F0034B, 78F0034B(A) and 78F0034A differ in the operating frequency ratings and communication mode of the flash memory programming. Refer to **5. DIFFERENCES BETWEEN** μ PD78F0034B, 78F0034BY AND μ PD78F0034A, 78F0034AY.
 - 2. The expanded-specification products and conventional products of the mask ROM versions differ in the operating frequency ratings. Refer to the data sheets of the products.
 - **3.** The special grade version of the μ PD78F0034A is not provided (only the standard grade version is provided).

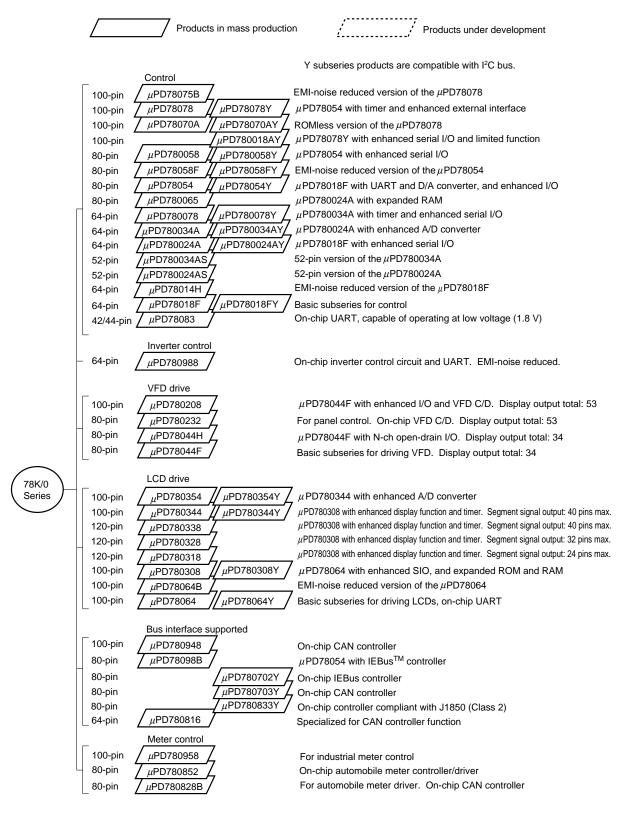
• μPD780024AY, 780034AY Subseries

Mask ROM Products	Flash Memory Products
μPD780021AY, 780022AY, 780023AY, 780024AY	μPD78F0034AY
μPD780031AY, 780032AY, 780033AY, 780034AY	μPD78F0034BY
μPD780021AY(A), 780022AY(A), 780023AY(A), 780024AY(A)	μPD78F0034BY(A)
μPD780031AY(A), 780032AY(A), 780033AY(A), 780034AY(A)	

- Remarks 1. The μ PD78F0034BY, 78F0034BY(A) and 78F0034AY differ in the communication mode of the flash memory programming. Refer to **5. DIFFERENCES BETWEEN** μ PD78F0034B, 78F0034BY AND μ PD78F0034A, 78F0034AY.
 - 2. The expanded-specification products of the μ PD780024AY, 780034AY Subseries are not provided (only the conventional products are provided).
 - **3.** The special grade version of the μ PD78F0034A is not provided (only the standard grade version is provided).

78K/0 SERIES LINEUP

The products in the 78K/0 Series are listed below. The names enclosed in boxes are subseries names.



Remark VFD (Vacuum Fluorescent Display) is referred to as FIPTM (Fluorescent Indicator Panel) in some documents, but the functions of the two are same.

The major functional differences among the subseries are listed below.

• Non-Y subseries

	Function	ROM Capacity			ner		8-Bit	10-Bit	8-Bit	Serial Interface	I/O	V _{DD}	External
Subseries	Name	(Bytes)	8-Bit	16-Bit	Watch	WDT	A/D	A/D	D/A			Value	Expansion
Control	μPD78075B	32 K to 40 K	4 ch	1 ch	1 ch	1 ch	8 ch	_	2 ch	3 ch (UART: 1 ch)	88	1.8 V	√
	μPD78078	48 K to 60 K											
	μPD78070A	-									61	2.7 V	
	μPD780058	24 K to 60 K	2 ch							3 ch (time-division UART: 1 ch)	68	1.8 V	
	μPD78058F	48 K to 60 K								3 ch (UART: 1 ch)	69	2.7 V	
	μPD78054	16 K to 60 K										2.0 V	
	μPD780065	40 K to 48 K							_	4 ch (UART: 1 ch)	60	2.7 V	
	μPD780078	48 K to 60 K		2 ch			_	8 ch		3 ch (UART: 2 ch)	52	1.8 V	
	μPD780034A	8 K to 32 K		1 ch						3 ch (UART: 1 ch)	51		
	μPD780024A						8 ch	_					
	μPD780034AS						_	4 ch			39		-
	μPD780024AS						4 ch	_					
	μPD78014H						8 ch			2 ch	53		√
	μPD78018F	8 K to 60 K											
	μPD78083	8 K to 16 K		_	-					1 ch (UART: 1 ch)	33		-
Inverter control	μPD780988	16 K to 60 K	3 ch	Note	-	1 ch	_	8 ch	_	3 ch (UART: 2 ch)	47	4.0 V	√
VFD	μPD780208	32 K to 60 K	2 ch	1 ch	1 ch	1 ch	8 ch	_	_	2 ch	74	2.7 V	_
drive	μPD780232	16 K to 24 K	3 ch	_	1		4 ch				40	4.5 V	
	μPD78044H	32 K to 48 K	2 ch	1 ch	1 ch		8 ch			1 ch	68	2.7 V	
	μPD78044F	16 K to 40 K								2 ch			
LCD	μPD780354	24 K to 32 K	4 ch	1 ch	1 ch	1 ch	_	8 ch	_	3 ch (UART: 1 ch)	66	1.8 V	_
drive	μPD780344						8 ch	_					
	μPD780338	48 K to 60 K	3 ch	2 ch			_	10 ch	1 ch	2 ch (UART: 1 ch)	54		
	μPD780328										62		
	μPD780318										70		
	μPD780308	48 K to 60 K	2 ch	1 ch			8 ch	_	_	3 ch (time-division UART: 1 ch)	57	2.0 V	
	μPD78064B	32 K								2 ch (UART: 1 ch)			
	μPD78064	16 K to 32 K											
Bus	μPD780948	60 K	2 ch	2 ch	1 ch	1 ch	8 ch	_	_	3 ch (UART: 1 ch)	79	4.0 V	√
interface	μPD78098B	40 K to 60 K		1 ch					2 ch		69	2.7 V	_
supported	μPD780816	32 K to 60 K		2 ch			12 ch		_	2 ch (UART: 1 ch)	46	4.0 V	
Meter control	μPD780958	48 K to 60 K	4 ch	2 ch	-	1 ch	_	-	_	2 ch (UART: 1 ch)	69	2.2 V	-
Dash-	μPD780852	32 K to 40 K	3 ch	1 ch	1 ch	1 ch	5 ch	-	-	3 ch (UART: 1 ch)	56	4.0 V	_
board control	μPD780828B	32 K to 60 K									59		

Note 16-bit timer: 2 channels 10-bit timer: 1 channel

• Y subseries

	Function	ROM Capacity		Tin	ner		8-Bit	10-Bit	8-Bit	Serial Interface	I/O	V _{DD}	External
Subseries	Name	(Bytes)	8-Bit	16-Bit	Watch	WDT	A/D	A/D	D/A				Expansion
Control	μPD78078Y	48 K to 60 K	4 ch	1 ch	1 ch	1 ch	8 ch	-	2 ch	3 ch (UART: 1 ch, I ² C: 1 ch)	88	1.8 V	√
	μPD78070AY	-									61	2.7 V	
	μPD780018AY	48 K to 60 K							_	3 ch (I ² C: 1 ch)	88		
	μPD780058Y	24 K to 60 K	2 ch						2 ch	3 ch (time-division UART: 1 ch, I ² C: 1 ch)	68	1.8 V	
	μPD78058FY	48 K to 60 K								3 ch (UART: 1 ch, I ² C: 1 ch)	69	2.7 V	
	μPD78054Y	16 K to 60 K										2.0 V	
	μPD780078Y	48 K to 60 K		2 ch			_	8 ch	_	4 ch (UART: 2 ch, I ² C: 1 ch)	52	1.8 V	
	μPD780034AY	8 K to 32 K		1 ch						3 ch (UART: 1 ch, I ² C: 1 ch)	51		
	μPD780024AY						8 ch	-					
	μPD78018FY	8 K to 60 K								2 ch (I ² C: 1 ch)	53		
LCD	μPD780354Y	24 K to 32 K	4 ch	1 ch	1 ch	1 ch	_	8 ch	-	4 ch (UART: 1 ch,	66	1.8 V	-
drive	μPD780344Y						8 ch	-		I ² C: 1 ch)			
	μPD780308Y	48 K to 60 K	2 ch							3 ch (time-division UART: 1 ch, I ² C: 1 ch)	57	2.0 V	
	μPD78064Y	16 K to 32 K								2 ch (UART: 1 ch, I ² C: 1 ch)			
Bus	μPD780701Y	60 K	3 ch	2 ch	1 ch	1 ch	16 ch	-	_	4 ch (UART: 1 ch, I ² C: 1 ch)	67	3.5 V	-
interface	μPD780703Y												
supported	μPD780833Y										65	4.5 V	

Remark Functions other than the serial interface are common to both the Y and non-Y subseries.



OVERVIEW OF FUNCTIONS

Item	Part Number	μPD78F0034B μPD78F0034B(A)	μPD78F0034BY μPD78F0034BY(A)				
Internal	Flash memory	32 KB ^{Note 1}					
memory	High-speed RAM	1,024 bytesNote 1					
Memory space		64 KB					
General-purpos	e registers	8 bits $ imes$ 32 registers (8 bits $ imes$ 8 registers $ imes$	4 banks)				
Minimum instru	ction execution time	On-chip minimum instruction execution tim	e cycle variable function				
	When main system	0.166 μ s/0.333 μ s/0.666 μ s/1.33 μ s/2.66 μ s (@ 12 MHz operation, V _{DD} = 4.5 to 5.5 V)	0.238 μ s/0.48 μ s/0.95 μ s/1.91 μ s/3.81 μ s (@ 8.38 MHz operation, V _{DD} = 4.0 to 5.5 V)				
	When subsystem clock selected	122 μs (@ 32.768 kHz operation)					
Instruction set		 16-bit operation Multiply/divide (8 bits × 8 bits, 16 bits ÷ 8 Bit manipulation (set, reset, test, Boolean BCD adjust, etc. 	,				
I/O ports		Total:	51				
		CMOS input: CMOS I/O: N-ch open-drain I/O (5 V withstand voltage)	8 39 ge): 4				
A/D converter		 10-bit resolution × 8 channels Operable over a wide power supply voltage range: AVDD = 1.8 to 5.5 V 					
Serial interface		UART mode: 1 channel 3-wire serial I/O mode: 2 channels	UART mode: 3-wire serial I/O mode: 1 channel 1/2 bus mode (multimaster supporting): 1 channel				
Timers		16-bit timer/event counter: 1 channel 8-bit timer/event counter: 2 channels Watch timer: 1 channel Watchdog timer: 1 channel					
Timer outputs		3 (8-bit PWM output capable: 2)					
Clock output		93.75 kHz, 187.5 kHz, 375 kHz, 750 kHz, 1.25 MHz, 3 MHz, 6 MHz, 12 MHz (@ 12 MHz operation with main system clock) 32.768 kHz (@ 32.768 kHz operation with subsystem clock)	 65.5 kHz, 131 kHz, 262 kHz, 524 kHz, 1.05 MHz, 2.10 MHz, 4.19 MHz, 8.38 MHz (@ 8.38 MHz operation with main system clock) 32.768 kHz (@ 32.768 kHz operation with subsystem clock) 				
Buzzer output		1.46 kHz, 2.93 kHz, 5.86 kHz, 11.7 kHz (@ 12 MHz operation with main system clock)	1.02 kHz, 2.05 kHz, 4.10 kHz, 8.19 kHz (@ 8.38 MHz operation with main system clock)				
Vectored interru	ıpt Maskable	Internal: 13, external: 5					
sources	Non-maskable	Internal: 1					
	Software	1					
Test inputs		Internal: 1, external: 1					
Supply voltage		V _{DD} = 1.8 to 5.5 V					
Operating ambient temperature		$T_A = -40 \text{ to } +85^{\circ}\text{C}$					
Package		64-pin plastic LQFP (10 x 10) 64-pin plastic LQFP (14 x 14) 64-pin plastic TQFP (12 x 12) 73-pin plastic FBGA (9 x 9) ^{Note 2}					

Notes 1. The capacities of the flash memory and the internal high-speed RAM can be changed with the memory size switching register (IMS).

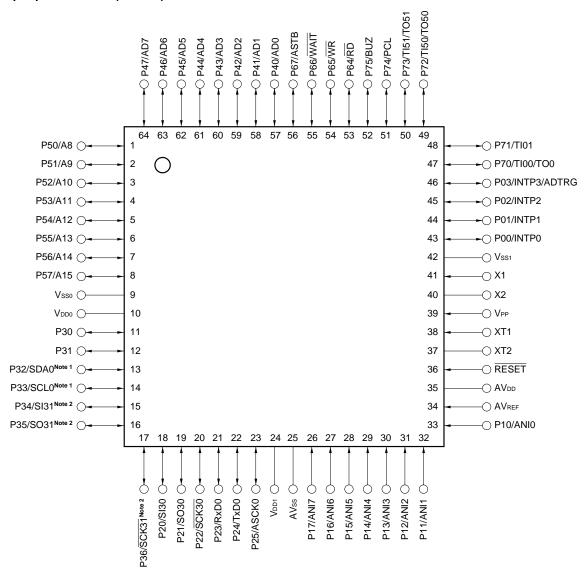
2. The special grade version of the 73-pin plastic FBGA (9 x 9) is not provided.

CONTENTS

1.	PIN CONFIGURATION (TOP VIEW)	9
2.	BLOCK DIAGRAM	12
3.	PIN FUNCTIONS	13
	3.1 Port Pins	13
	3.2 Non-Port Pins	14
	3.3 Pin I/O Circuits and Recommended Connection of Unused Pins	16
4.	DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY, AND MASK ROM VERSIONS	19
5.	DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY AND μ PD78F0034A, 78F0034AY	21
6.	DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY AND μ PD78F0034B(A), 78F0034BY(A)	22
7.	MEMORY SIZE SWITCHING REGISTER (IMS)	23
8.	FLASH MEMORY PROGRAMMING	24
	8.1 Selection of Communication Mode	24
	8.2 Flash Memory Programming Functions	26
	8.3 Connection of Flashpro III/Flashpro IV	26
9.	ELECTRICAL SPECIFICATIONS	28
	9.1 μPD78F0034B, 78F0034B(A)	28
	9.2 μPD78F0034BY, 78F0034BY(A)	46
	9.3 Timing Chart	64
10	PACKAGE DRAWINGS	71
11.	RECOMMENDED SOLDERING CONDITIONS	75
ΑP	PENDIX A. DEVELOPMENT TOOLS	77
ΑP	PENDIX B. RELATED DOCUMENTS	85

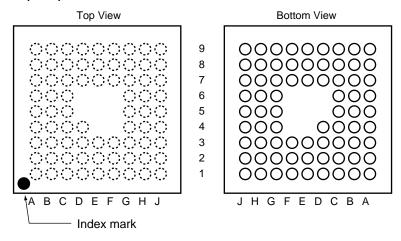
1. PIN CONFIGURATION (TOP VIEW)

- 64-pin plastic LQFP (10 x 10)
- 64-pin plastic TQFP (12 x 12)
- 64-pin plastic LQFP (14 x 14)



- Notes 1. SDA0 and SCL0 are incorporated only in the μPD78F0034BY, 78F0034BY(A) Subseries.
 - 2. SI31, SO31, and $\overline{SCK31}$ are incorporated only in the μ PD78F0034B, 78F0034B(A) Subseries.
- Cautions 1. Connect the VPP pin directly to Vsso or Vss1 in normal operation mode.
 - 2. Connect the AVss pin to Vsso.
- Remark When the μPD78F0034B, 78F0034BY, 78F0034B(A), and 78F0034BY(A) are used in application fields that require reduction of the noise generated from inside the microcontroller, the implementation of noise reduction measures, such as supplying voltage to V_{DD0} and V_{DD1} individually and connecting Vsso and Vss1 to different ground lines, is recommended.

• 73-pin plastic FBGA (9 x 9)



Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name	Pin No.	Pin Name
A1	NC	C1	P52/A10	E1	P57/A15	G1	P33/SCL0 ^{Note 1}	J1	NC
A2	P46/AD6	C2	P53/A11	E2	V _{DD0}	G2	P32/SDA0 ^{Note 1}	J2	P36/SCK31Note2
А3	P44/AD4	C3	P45/AD5	E3	P54/A12	G3	P20/SI30	J3	NC
A4	P41/AD1	C4	P42/AD2	E4	_	G4	P21/SO30	J4	P25/ASCK0
A5	P67/ASTB	C5	P64/RD	E5	_	G5	P24/TxD0	J5	NC
A6	P65/WR	C6	P73/TI51/TO51	E6	_	G6	V _{DD1}	J6	P17/ANI7
A7	P74/PCL	C7	P03/INTP3/ADTRG	E7	P00/INTP0	G7	P16/ANI6	J7	P12/ANI2
A8	NC	C8	P01/INTP1	E8	XT1	G8	AV _{DD}	J8	P13/ANI3
A9	NC	C9	Vss1	E9	X2	G9	NC	J9	NC
B1	P51/A9	D1	P55/A13	F1	P30	H1	P34/SI31Note 2		
B2	P47/AD7	D2	P56/A14	F2	P31	H2	P35/SO31 ^{Note 2}		
ВЗ	P43/AD3	D3	P50/A8	F3	Vsso	НЗ	P23/RxD0		
B4	P40/AD0	D4	NC	F4	_	H4	P22/SCK30		
B5	P66/WAIT	D5	_	F5	_	H5	AVss		
В6	P75/BUZ	D6	_	F6	_	H6	P15/ANI5		
В7	P72/TI50/TO51	D7	P02/INTP2	F7	P14/ANI4	H7	P11/ANI1		
В8	P71/TI01	D8	VPP	F8	RESET	H8	P10/ANI0		
В9	P70/TI00/TO0	D9	X1	F9	XT2	H9	AVREF		

- **Notes 1.** SDA0 and SCL0 are incorporated only in the μ PD78F0034BY Subseries.
 - **2.** SI31, SO31, and $\overline{\text{SCK31}}$ are incorporated only in the μ PD78F0034B Subseries.
- Cautions 1. Connect the VPP pin directly to Vsso or Vss1 in normal operation mode.
 - 2. Connect the AVss pin to Vsso.
- Remarks 1. When the μPD78F0034B, 78F0034BY, 78F0034B(A), and 78F0034BY(A) are used in application fields that require reduction of the noise generated from inside the microcontroller, the implementation of noise reduction measures, such as supplying voltage to V_{DD0} and V_{DD1} individually and connecting V_{SS0} and V_{SS1} to different ground lines, is recommended.
 - 2. The special grade version of the 73-pin plastic FBGA (9 x 9) is not provided.

A8 to A15: Address bus P70 to P75: Port 7

AD0 to AD7: Address/data bus PCL: Programmable clock

ADTRG: AD trigger input $\overline{\text{RD}}$: Read strobe

ANI0 to ANI7: Analog input RESET: Reset

ASCK0: Asynchronous serial clock RxD0: Receive data

ASTB: Address strobe SCK30, SCK31, SCL0: Serial clock

AVDD: Analog power supply SDA0: Serial data

AVREF: Analog reference voltage SI30, SI31: Serial input

AVss: Analog ground SO30, SO31: Serial output

BUZ: Buzzer clock TI00, TI01, TI50, TI51: Timer input
INTP0 to INTP3: External interrupt input TO0, TO50, TO51: Timer output
NC: No connection TxD0: Transmit data

P00 to P03: Port 0 VDD0, VDD1: Power supply

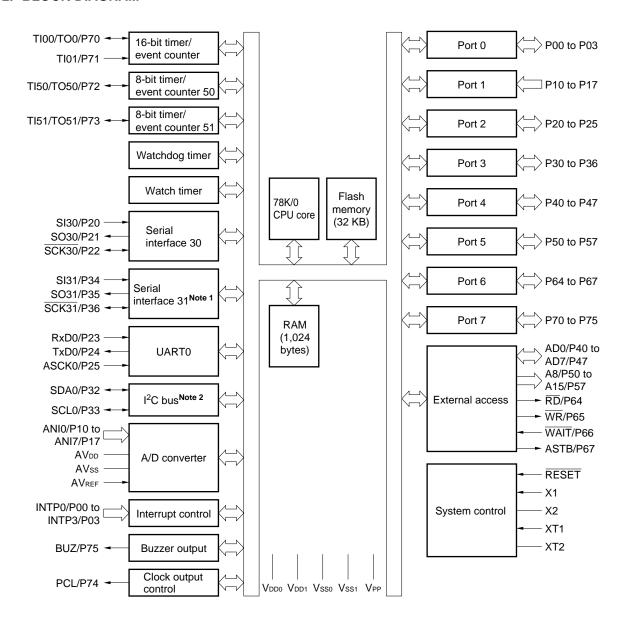
P10 to P17: Port 1 VPP: Programming power supply

P20 to P25: Port 2 Vsso, Vss1: Ground P30 to P36: Port 3 WAIT: Wait

P40 to P47: Port 4 \overline{WR} : Write strobe

P50 to P57: Port 5 X1, X2: Crystal (main system clock)
P64 to P67: Port 6 XT1, XT2: Crystal (subsystem clock)

2. BLOCK DIAGRAM



Notes 1. Incorporated only in the μ PD78F0034B and 78F0034B(A)

2. Incorporated only in the μ PD78F0034BY and 78F0034BY(A)

3. PIN FUNCTIONS

3.1 Port Pins (1/2)

Pin Name	I/O		Function	After Reset	Alternate Function
P00	I/O	Port 0		Input	INTP0
P01		4-bit I/O port.			INTP1
P02		Input/output can be specified			INTP2
P03		An on-chip pull-up resistor ca	n be specified by software.		INTP3/ADTRG
P10 to P17	Input	Port 1 8-bit input-only port.		Input	ANI0 to ANI7
P20	I/O	Port 2		Input	SI30
P21		6-bit I/O port.			SO30
P22]	Input/output can be specified An on-chip pull-up resistor ca			SCK30
P23		All off-chip pull-up resistor ca	n be specified by software.		RxD0
P24					TxD0
P25					ASCK0
P30	I/O	Port 3	N-ch open-drain I/O port.	Input	-
P31		7-bit I/O port.	LEDs can be driven directly.		
P32		Input/output can be specified			SDA0Note 1
P33		in 1-bit units.			SCL0Note 1
P34			An on-chip pull-up resistor can be		SI31 Note 2
P35	-		specified by software.		SO31Note 2
P36					SCK31 Note 2
P40 to P47	I/O	Port 4 8-bit I/O port. Input/output can be specified An on-chip pull-up resistor ca Interrupt request flag KRIF is		Input	AD0 to AD7
P50 to P57	I/O	Port 5 8-bit I/O port. LEDs can be driven directly. Input/output can be specified An on-chip pull-up resistor ca	Input	A8 to A15	
P64	I/O	Port 6		Input	RD
P65	1	4-bit I/O port.			WR
P66	1	Input/output can be specified			WAIT
P67	1	An on-chip pull-up resistor ca	n be specified by software.		ASTB

Notes 1. SDA0 and SCL0 are incorporated only in the μ PD78F0034BY and 78F0034BY(A).

2. SI31, SO31, and $\overline{\text{SCK31}}$ are incorporated only in the μ PD78F0034B and 78F0034B(A).

3.1 Port Pins (2/2)

Pin Name	I/O	Function	After Reset	Alternate Function
P70	I/O	Port 7	Input	TI00/TO0
P71		6-bit I/O port.		TI01
P72		Input/output can be specified in 1-bit units. An on-chip pull-up resistor can be specified by software.		TI50/TO50
P73		All oil-oilly pull-up resistor can be specified by software.		TI51/TO51
P74				PCL
P75				BUZ

3.2 Non-Port Pins (1/2)

Pin Name	I/O	Function	After Reset	Alternate Function
INTP0	Input	External interrupt request input by which the valid edge (rising edge,	Input	P00
INTP1		falling edge, or both rising and falling edges) can be specified.		P01
INTP2				P02
INTP3				P03/ADTRG
SI30	Input	Serial interface serial data input.	Input	P20
SI31Note 1				P34
SDA0 ^{Note 2}	I/O	Serial interface serial data input/output	Input	P32
SO30	Output	Serial interface serial data output.	Input	P21
SO31 ^{Note 1}				P35
SCK30	I/O	Serial interface serial clock input/output.	Input	P22
SCK31 Note 1				P36
SCL0Note 2				P33
RxD0	Input	Serial data input for asynchronous serial interface.	Input	P23
TxD0	Output	Serial data output for asynchronous serial interface.	Input	P24
ASCK0	Input	Serial clock input for asynchronous serial interface.	Input	P25
TI00	Input	External count clock input to 16-bit timer/event counter 0. Capture trigger signal input to capture register 01 (CR01) of 16-bit timer/event counter 0.	Input	P70/TO0
TI01		Capture trigger signal input to capture register 00 (CR00) of 16-bit timer/ event counter 0.		P71
TI50		External count clock input to 8-bit timer/event counter 50.		P72/TO50
TI51		External count clock input to 8-bit timer/event counter 51.		P73/TO51
TO0	Output	16-bit timer/event counter 0 output.	Input	P70/TI00
TO50		8-bit timer/event counter 50 output (shared with 8-bit PWM output).	Input	P72/TI50
TO51		8-bit timer/event counter 51 output (shared with 8-bit PWM output).		P73/TI51
PCL	Output	Clock output (for trimming of main system clock and subsystem clock).	Input	P74
BUZ	Output	Buzzer output.	Input	P75
AD0 to AD7	I/O	Lower address/data bus for extending memory externally.	Input	P40 to P47

Notes 1. SI31, SO31, and $\overline{\text{SCK31}}$ are incorporated only in the μ PD78F0034B and 78F0034B(A).

2. SDA0 and SCL0 are incorporated only in the μ PD78F0034BY and 78F0034BY(A).

3.2 Non-Port Pins (2/2)

Pin Name	I/O	Function	After Reset	Alternate Function
A8 to A15	Output	Higher address bus for extending memory externally.	Input	P50 to P57
RD	Output	Strobe signal output for read operation of external memory.	Input	P64
WR		Strobe signal output for write operation of external memory.]	P65
WAIT	Input	Inserting wait for accessing external memory.	Input	P66
ASTB	Output	Strobe output which externally latches address information output to ports 4 and 5 to access external memory.	Input	P67
ANI0 to ANI7	Input	A/D converter analog input.	Input	P10 to P17
ADTRG	Input	A/D converter trigger signal input.	Input	P03/INTP3
AVREF	Input	A/D converter reference voltage input.	_	_
AVDD	-	A/D converter analog power supply. Set the voltage equal to V _{DD0} or V _{DD1} .	_	-
AVss	-	A/D converter ground potential. Set the voltage equal to Vsso or Vss1.	_	-
RESET	Input	System reset input.	-	_
X1	Input	Connecting crystal resonator for main system clock oscillation.	_	-
X2	_		_	_
XT1	Input	Connecting crystal resonator for subsystem clock oscillation.	_	_
XT2	-		_	-
V _{DD0}	_	Positive power supply voltage for ports.	_	-
Vsso	-	Ground potential of ports.	_	-
V _{DD1}	-	Positive power supply (except ports).	_	_
Vss1	_	Ground potential (except ports).	_	-
VPP	-	Applying high-voltage for program write/verify. Connect to Vsso or Vsso in normal operation mode.	-	-
NC ^{Note}	-	Not internally connected. Leave open.	-	-

Note NC is incorporated only in the 73-pin plastic FBGA.

3.3 Pin I/O Circuits and Recommended Connection of Unused Pins

The input/output circuit type of each pin and recommended connection of unused pins are shown in Table 3-1. For the input/output configuration of each type, refer to Figure 3-1.

Table 3-1. Types of Pin I/O Circuits (1/2)

Pin Name	I/O Circuit Type	I/O	Recommended Connection of Unused Pins
P00/INTP0	8-C	I/O	Input: Independently connect to Vsso or Vss1 via a
P01/INTP1			via a resistor.
P02/INTP2			Output: Leave open.
P03/INTP3/ADTRG			
P10/ANI0 to P17/ANI7	25	Input	Directly connect to VDD0, VDD1, VSS0, or VSS1.
P20/SI30	8-C	I/O	Input: Independently connect to VDD0, VDD1, VSS0, or
P21/SO30	5-H		V _{SS1} via a resistor.
P22/SCK30	8-C		Output: Leave open.
P23/RxD0			
P24/TxD0	5-H		
P25/ASCK0	8-C		
P30, P31	13-P		Input: Directly connect to Vsso or Vss1.
P32/SDA0 ^{Note 1}	13-R		Output: Leave open at low-level output.
P33/SCL0Note 1			
P34/SI31Note 2	8-C		Input: Independently connect to VDD0, VDD1, VSS0 or
P35/SO31Note 2	5-H		Vss1 via a resistor.
P36/SCK31Note 2	8-C		Output: Leave open.
P40/AD0 to P47/AD7	5-H		Input: Independently connect to VDDO or VDD1 via a resistor. Output: Leave open.
P50/A8 to P57/A15	5-H	_	Input: Independently connect to VDD0, VDD1, VSS0, or
P64/RD			Vss1 via a resistor.
P65/WR			Output: Leave open.
P66/WAIT			
P67/ASTB			
P70/TI00/TO0	8-C		
P71/TI01			
P72/TI50/TO50			
P73/TI51/TO51			
P74/PCL	5-H	1	
P75/BUZ			

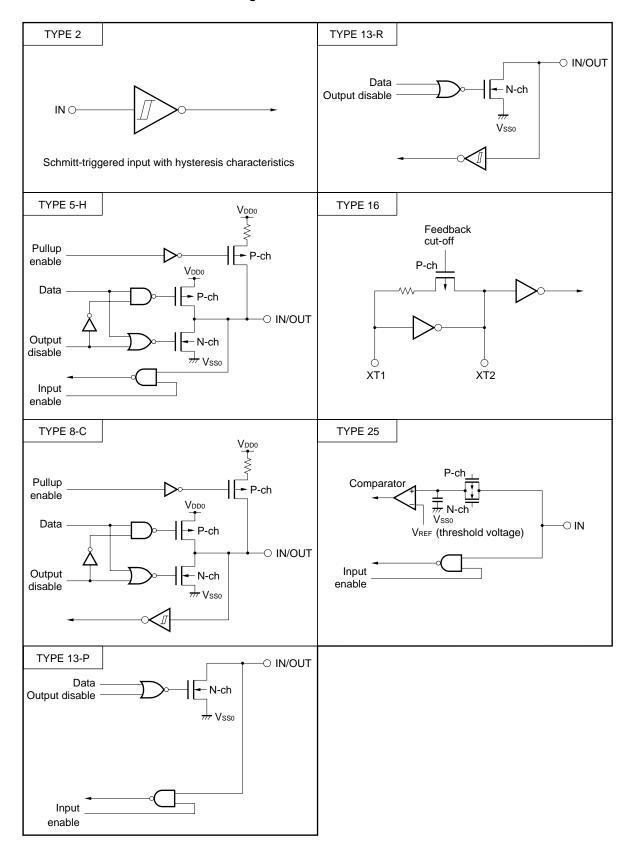
Notes 1. SDA0 and SCL0 are incorporated only in the μ PD78F0034BY and 78F0034BY(A).

2. SI31, SO31, and $\overline{\text{SCK31}}$ are incorporated only in the $\mu\text{PD78F0034B}$ and 78F0034B(A).

Table 3-1. Types of Pin I/O Circuits (2/2)

Pin Name	I/O Circuit Type	I/O	Recommended Connection of Unused Pins
RESET	2	Input	_
XT1	16		Directly connect to VDD0 or VDD1.
XT2		_	Leave open.
AV _{DD}	_		Directly connect to VDD0 or VDD1.
AVREF			Directly connect to Vsso or Vss1.
AVss			
VPP			Connect to Vsso or Vss1.

Figure 3-1. Pin I/O Circuits



4. DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY, AND MASK ROM VERSIONS

The μ PD78F0034B and 78F0034BY are products provided with a flash memory which enables writing, erasing, and rewriting of programs with device mounted on the target system.

The functions of the μ PD78F0034B and 78F0034BY (except the functions specified for flash memory) can be made the same as those of the mask ROM versions by setting the memory size switching register (IMS).

Tables 4-1 and 4-2 show the differences between the μ PD78F0034B, 78F0034BY and the mask ROM versions.

Table 4-1. Differences Between μPD78F0034B and Mask ROM Versions

Item	μPD78F0034B	Mask ROM	M Versions	
		μPD780034A Subseries	μPD780024A Subseries ^{Note}	
Internal ROM structure	Flash memory	Mask ROM		
Internal ROM capacity	32 KB	μPD780031A: 8 KB μPD780032A: 16 KB μPD780033A: 24 KB μPD780034A: 32 KB	μPD780021A: 8 KB μPD780022A: 16 KB μPD780023A: 24 KB μPD780024A: 32 KB	
Internal high-speed RAM capacity	1,024 bytes	μPD780031A: 512 bytes μPD780032A: 512 bytes μPD780033A: 1,024 bytes μPD780034A: 1,024 bytes	μPD780021A: 512 bytes μPD780022A: 512 bytes μPD780023A: 1,024 bytes μPD780024A: 1,024 bytes	
Minimum instruction execution time	Minimum instruction execut	on time variable function inco	rporated	
When main system clock is selected	selected < μ PD78F0034B and expanded-specification products of the mask ROM versi 0.166 μ s/0.333 μ s/0.666 μ s/1.33 μ s/2.66 μ s (@ 12 MHz operation, V _{DD} = 4.5 to <conventional mask="" of="" products="" rom="" the="" versions=""> 0.238 μs/0.48 μs/0.95 μs/1.91 μs/3.81 μs (@ 8.38 MHz operation, V_{DD} = 4.0 to</conventional>			
When subsystem clock is selected	122 μs (32.768 kHz)			
Clock output	 <μPD78F0034B and expanded-specification products of the mask ROM versions> • 93.75 kHz, 187.5 kHz, 375 kHz, 750 kHz, 1.25 MHz, 3 MHz, 6 MHz, 12 MHz (@ 12 MHz operation with main system clock) • 32.768 kHz (@ 32.768 kHz operation with subsystem clock) <conventional mask="" of="" products="" rom="" the="" versions=""></conventional> • 65.5 kHz, 131 kHz, 262 kHz, 524 kHz, 1.05 MHz, 2.10 MHz, 4.19 MHz, 8.38 MHz (@ 8.38 MHz operation with main system clock) • 32.768 kHz (@ 32.768 kHz operation with subsystem clock) 			
Buzzer output	<μPD78F0034B and expanded-specification products of the mask ROM versions> 1.46 kHz, 2.93 kHz, 5.86 kHz, 11.7 kHz (@ 12 MHz operation with main system clock) <conventional mask="" of="" products="" rom="" the="" versions=""> • 1.02 kHz, 2.05 kHz, 4.10 kHz, 8.19 kHz (@ 8.38 MHz operation with main system clock)</conventional>			
A/D converter resolution	10 bits		8 bits	
Mask option specification of on-chip pull-up resistor for pins P30 to P33	Not available	Available		
IC pin	Not provided	Provided		
V _{PP} pin	Provided	Not provided		
Electrical specifications, recommended soldering conditions	Refer to the data sheet of ir	ndividual products.		

Note The μ PD78F0034B can be used as the flash memory version of the μ PD780024A Subseries.

Caution There are differences in noise immunity and noise radiation between the flash memory and mask ROM versions. When pre-producing an application set with the flash memory version and then mass producing it with the mask ROM version, be sure to conduct sufficient evaluations on the commercial samples (CS) (not engineering samples (ES)) of the mask ROM versions.

Table 4-2. Differences Between μPD78F0034BY and Mask ROM Versions

Item	μPD78F0034BY	Mask ROM	M Versions
		μPD780034AY Subseries	μPD780024AY Subseries ^{Note}
Internal ROM structure	Flash memory	Mask ROM	
Internal ROM capacity	32 KB	μPD780031AY: 8 KB μPD780032AY: 16 KB μPD780033AY: 24 KB μPD780034AY: 32 KB	μPD780021AY: 8 KB μPD780022AY: 16 KB μPD780023AY: 24 KB μPD780024AY: 32 KB
Internal high-speed RAM capacity	1,024 bytes	μPD780031AY: 512 bytes $μ$ PD780032AY: 512 bytes $μ$ PD780033AY: 1,024 bytes $μ$ PD780034AY: 1,024 bytes	'
Minimum instruction execution time	Minimum instruction execut	on time variable function inco	rporated
When main system clock is selected	d 0.238 μ s/0.48 μ s/0.95 μ s/1.91 μ s/3.81 μ s (operation at 8.38 MHz, $V_{DD} = 4.0$ to 5.5 V)		
When subsystem clock is selected	122 μs (32.768 kHz)		
Clock output	 65.5 kHz, 131 kHz, 262 kHz, 524 kHz, 1.05 MHz, 2.10 MHz, 4.19 MHz, 8.38 MHz (@ 8.38 MHz operation with main system clock) 32.768 kHz 32.768 kHz operation with subsystem clock) 		
Buzzer output	1.02 kHz, 2.05 kHz, 4.10 kHz, 8.19 kHz (@ 8.38 MHz operation with main system clock)		
A/D converter resolution	10 bits		8 bits
Mask option specification of on-chip pull-up resistor for pins P30 and P31	Not available	Available	
IC pin	Not provided	Provided	
VPP pin	Provided	Not provided	
Electrical specifications, recommended soldering conditions	Refer to the data sheet of individual products.		

Note The μ PD78F0034BY can be used as the flash memory version of the μ PD780024AY Subseries.

Caution There are differences in noise immunity and noise radiation between the flash memory and mask ROM versions. When pre-producing an application set with the flash memory version and then mass producing it with the mask ROM version, be sure to conduct sufficient evaluations on the commercial samples (CS) (not engineering samples (ES)) of the mask ROM versions.

5. DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY AND μ PD78F0034A, 78F0034AY

Table 5-1 shows the differences between the μ PD78F0034B and μ PD78F0034A, and Table 5-2 shows differences between the μ PD78F0034BY and 78F0034AY.

Table 5-1. Differences Between μ PD78F0034B and μ PD78F0034A

	Item		μPD78F0034B	μPD78F0034A	
Guaranteed operating speed 4.5 to 5.5 V		12 MHz (0.166 μs)	8.38 MHz (0.238 μs)		
(operatir	ng frequency)	4.0 to 5.5 V	8.38 MHz (0.238 μs)	8.38 MHz (0.238 μs)	
		3.0 to 5.5 V	8.38 MHz (0.238 μs)	5 MHz (0.4 μs)	
		2.7 to 5.5 V	5 MHz (0.4 μs)	5 MHz (0.4 μs)	
		1.8 to 5.5 V	1.25 MHz (1.6 μs)	1.25 MHz (1.6 μs)	
Maximu	m instruction execution	time	Minimum instruction execution time va	ariable function incorporated	
	When main system cl	ock is selected	0.166 μs/0.333 μs/0.666 μs/1.33 μs/2.66 μs (@ 12 MHz operation, Vpp = 4.5 to 5.5 V)	0.238 μ s/0.48 μ s/0.95 μ s/1.91 μ s/3.81 μ s (@ 8.38 MHz operation, $V_{DD} = 4.0$ to 5.5 V)	
	When subsystem cloc	k is selected	122 μs (32.768 kHz)		
Clock output		93.75 kHz, 187.5 kHz, 375 kHz, 750 kHz, 1.25 MHz, 3 MHz, 6 MHz, 12 MHz (@ 12 MHz operation with main system clock) 32.768 kHz (@ 32.768 kHz operation with subsystem clock)	 65.5 kHz, 131 kHz, 262 kHz, 524 kHz, 1.05 MHz, 2.10 MHz, 4.19 MHz, 8.38 MHz (@ 8.38 MHz operation with main system clock) 32.768 kHz (@ 32.768 kHz operation with subsystem clock) 		
Buzzer	output		1.46 kHz, 2.93 kHz, 5.86 kHz, 11.7 kHz (@ 12 MHz operation with main system clock)	1.02 kHz, 2.05 kHz, 4.10 kHz, 8.19 kHz (@ 8.38 MHz operation with main system clock)	
Communication mode of flash memory programming		3-wire serial I/O: 2 channels ^{Note} UART: 1 channel Pseudo 3-wire serial I/O: 1 channel	3-wire serial I/O: 2 channels Note UART: 1 channel Pseudo 3-wire serial I/O: 1 channel		
	al specifications, recomm g conditions	mended	Refer to the data sheet of individual p	roducts.	

Note The μ PD78F0034B can use one channel (serial interface SIO30) as a handshake mode. The μ PD78F0034A cannot use a handshake mode.

Remark The operating frequency ratings of the μ PD78F0034B and the expanded-specification products of the mask ROM versions of the μ PD780024A, 780034A Subseries are the same. The operating frequency ratings of the μ PD78F0034A and the conventional products of the mask ROM versions of the μ PD780024A, 780034A Subseries are the same.

Table 5-2. Differences Between μPD78F0034BY and μPD78F0034AY

	Item		μPD78F0	034BY	μPD78F00	34AY
Guaranteed operating speed 4.5 to 5.5 V			8.38 MHz (0.238 μs)			
(operati	ng frequency)	4.0 to 5.5 V	8.38 MHz (0.238 μs	·)		
		3.0 to 5.5 V	5 MHz (0.4 μs)			
		2.7 to 5.5 V	5 MHz (0.4 μs)			
		1.8 to 5.5 V	1.25 MHz (1.6 μs)			
Maximu	m instruction execution	time	Minimum instruction	execution time v	ariable function incorp	orated
	When main system cl	ock is selected	0.238 μs/0.48 μs/0.4 4.0 to 5.5 V)	95 μs/1.91 μs/3.8°	1 μs (@ 8.38 MHz ope	ration, V _{DD} =
	When subsystem cloc	k is selected	122 μs (32.768 kHz)		
Clock or	utput		 65.5 kHz, 131 kHz, 262 kHz, 524 kHz, 1.05 MHz, 2.10 MHz, 4.19 MHz, 8.38 MHz (@ 8.38 MHz operation with main system clock) 32.768 kHz (@ 32.768 kHz operation with subsystem clock) 			
Buzzer	output		1.02 kHz, 2.05 kHz, system clock)	4.10 kHz, 8.19 kl	Hz (@ 8.38 MHz opera	ation with main
Communication mode of flash memory programming		 3-wire serial I/O: 2 channels Note UART: 1 channel Pseudo 3-wire serial I/O: 1 channel 3-wire serial I/O: 2 channels Note UART: 1 channel Pseudo 3-wire serial I/O: 1 channel Pseudo 3-wire serial I/O: 1 channel 				
	al specifications, recomr	nended	Refer to the data sh	eet of individual p	products.	

Note The μ PD78F0034BY can use one channel (serial interface SIO30) as a handshake mode. The μ PD78F0034AY cannot use a handshake mode.

Remark The operating frequency ratings of the μ PD78F0034BY, 78F0034AY and the mask ROM versions of the μ PD780024AY, 780034AY Subseries are the same.

6. DIFFERENCES BETWEEN μ PD78F0034B, 78F0034BY AND μ PD78F0034B(A), 78F0034BY(A)

The μ PD78F0034(A) and 78F0034BY(A) are products to which a quality assurance program more stringent than that used for the μ PD780034B and 780034BY (standard models) is applied (NEC Electronics classifies these products as "special" quality grade models).

The μ PD78F0034BY and μ PD78F0034B(A), 78F0034BY(A) only differ in the quality grade; there are no differences in functions and electrical specifications.

Table 6-1. Differences Between μ PD78F0034B, 78F0034BY and μ PD78F0034B(A), 78F0034BY(A)

Item	μPD78F0034B, 78F0034BY	μPD78F0034B(A), 78F0034BY(A)
Quality grade	Standard	Special
Functions and electrical specifications	No differences.	

7. MEMORY SIZE SWITCHING REGISTER (IMS)

IMS is a register that is set by software and is used to specify a part of the internal memory that is not to be used. By setting memory size switching register (IMS), the internal memory of the μ PD78F0034B, 78F0034BY, 78F0034B(A), and 78F0034BY(A) can be mapped identically to that of a mask ROM version.

IMS is set with an 8-bit memory manipulation instruction.

RESET input sets IMS to CFH.

Caution The initial value of IMS is setting disabled (CFH). Be sure to set C8H or the value of the target mask ROM version at the moment of initial setting.

3 2 0 Address After reset R/W IMS RAM0 ROM3 ROM2 ROM1 ROM0 FFF0H CFH RAM2 RAM1 R/W ROM3 ROM2 ROM1 ROM0 Selection of Internal ROM Capacity 0 8 KB 0 1 0 0 1 0 16 KB 0 0 1 1 24 KB 1 0 0 32 KB Other than above Setting prohibited RAM2 RAM1 RAM0 Selection of Internal High-Speed RAM Capacity 0 0 1 512 bytes 1 1 0 1,024 bytes Other than above Setting prohibited

Figure 7-1. Format of Memory Size Switching Register

Table 7-1 shows the IMS set value to make the memory mapping the same as those of mask ROM versions.

 Target Mask ROM Versions
 IMS Set Value

 μPD780021A, 780021AY, 780031A, 780031AY
 42H

 μPD780022A, 780022AY, 780032A, 780032AY
 44H

 μPD780023A, 780023AY, 780033A, 780033AY
 C6H

 μPD780024A, 780024AY, 780034A, 780034AY
 C8H

Table 7-1. Set Value of Memory Size Switching Register

8. FLASH MEMORY PROGRAMMING

Writing to flash memory can be performed without removing the memory from the target system (on board programming). Writing is performed with the dedicated flash programmer (Flashpro III (part No.: FL-PR3 and PG-FP3)/(Flashpro IV (part No.: FL-PR4 and PG-FP4)) connected to the host machine and the target system.

Writing to flash memory can also be performed using flash memory writing adapter connected to Flashpro III/ Flashpro IV.

Remark FL-PR3 and FL-PR4 are products of Naito Densei Machida Mfg. Co., Ltd.

8.1 Selection of Communication Mode

Writing to a flash memory is performed using Flashpro III/Flashpro IV in a serial communication. Select one of the communication modes in Tables 8-1 and 8-2. The selection of the communication mode is made by using the format shown in Figure 8-1. Each communication mode is selected by the number of VPP pulses shown in Tables 8-1 and 8-2.

Table 8-1. List of Communication Mode (μ PD78F0034B)

Communication Mode	Channels	Pin Used	V _{PP} Pulses
3-wire serial I/O	2	SI30/P20 SO30/P21 SCK30/P22	0
		SI31/P34 SO31/P35 SCK31/P36	1
		SI30/P20 SO30/P21 SCK30/P22 HS/P25	3
UART	1	RxD0/P23 TxD0/P24	8
Pseudo 3-wire serial I/O	1	P72/TI50/TO50 (serial clock input) P71/TI01 (serial data output) P70/TI00/TO0 (serial data input)	12

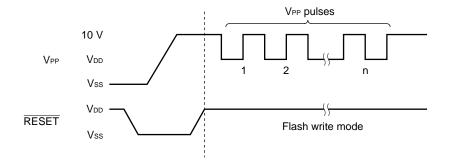
Caution Be sure to select a communication mode using the number of VPP pulses shown in Table 8-1.

Table 8-2. List of Communication Mode (μPD78F0034BY)

Communication Mode	Channels	Pin Used	V _{PP} Pulses
3-wire serial I/O	1	SI30/P20 SO30/P21 SCK30/P22	0
		SI30/P20 SO30/P21 SCK30/P22 HS/P25	3
I ² C bus	1	SDA0/P32 SCL0/P33	4
UART	1	RxD0/P23 TxD0/P24	8
Pseudo 3-wire serial I/O	1	P72/TI50/TO50 (serial clock input) P71/TI01 (serial data output) P70/TI00/TO0 (serial data input)	12

Caution Be sure to select a communication mode using the number of VPP pulses shown in Table 8-2.

Figure 8-1. Format of Communication Mode Selection



8.2 Flash Memory Programming Functions

Operations such as writing to flash memory are performed by various command/data transmission and reception operations according to the selected communication mode. Table 8-3 shows major functions of flash memory programming.

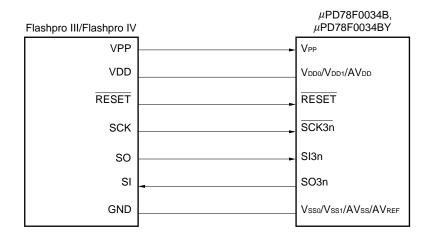
Table 8-3. Major Functions of Flash Memory Programming

Function	Description
Reset	Used to stop write operation and detect transmission cycle.
Batch verify	Compares the entire memory contents with the input data.
Batch erase	Erases the entire memory contents.
Batch blank check	Checks the deletion status of the entire memory.
High-speed write	Performs write to the flash memory based on the write start address and the number of data to be written (number of bytes).
Continuous write	Performs continuous write based on the information input with high-speed write operation.
Status	Used to confirm the current operating mode and operation end.
Oscillation frequency setting	Sets the frequency of the resonator.
Erase time setting	Sets the memory erase time.
Baud rate setting	Sets the communication rate for UART mode
I ² C mode setting	Sets standard/high-speed mode for I ² C bus mode
Silicon signature read	Outputs the device name and memory capacity, and device block information.

8.3 Connection of Flashpro III/Flashpro IV

The connection of Flashpro III/Flashpro IV and the μ PD78F0034B or 78F0034BY differs according to the communication mode (3-wire serial I/O, UART, pseudo 3-wire serial I/O, and I²C bus). The connection for each communication mode is shown in Figures 8-2 to 8-6, respectively.

Figure 6-2. Connection of Flashpro III/Flashpro IV in 3-Wire Serial I/O Mode



Remark μ PD78F0034B: n = 0, 1

 μ PD78F0034BY: n = 0

Figure 8-3. Connection of Flashpro III in 3-Wire Serial I/O Mode (Using Handshake)

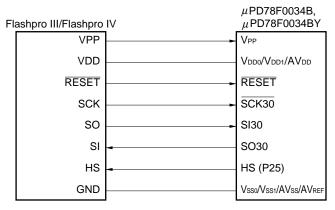


Figure 8-4. Connection of Flashpro III/Flashpro IV for UART Mode

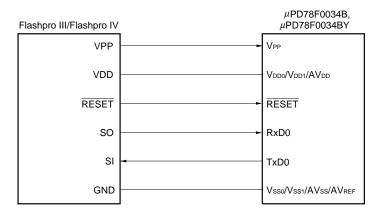


Figure 8-5. Connection of Flashpro III/Flashpro IV for Pseudo 3-Wire Serial I/O Mode

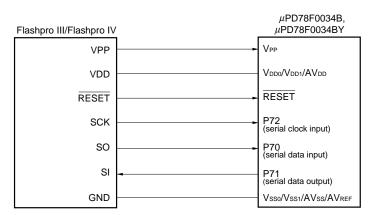
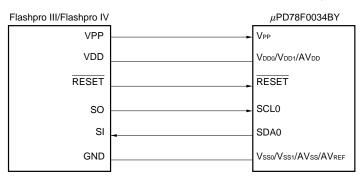


Figure 8-6. Connection of Flashpro III/Flashpro IV for I²C Bus Mode (μPD78F0034BY only)



9. ELECTRICAL SPECIFICATIONS

9.1 μ PD78F0034B, 78F0034B(A)

Absolute Maximum Ratings (T_A = 25°C)

Parameter	Symbol		Conditions	Ratings	Unit
Supply voltage	V _{DD}			-0.3 to +6.5	V
	VPP	Note 2		-0.3 to +10.5	V
	AV _{DD}			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	AVREF			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	AVss			-0.3 to +0.3	V
Input voltage	Vıı	· ·	P10 to P17, P20 to P25, P34 to P36, P50 to P57, P64 to P67, P70 to P75, XT2, RESET	-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	V ₁₂	P30 to P33	N-ch open drain	-0.3 to +6.5	V
Output voltage	Vo			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
Analog input voltage	Van	P10 to P17	Analog input pin	AVss -0.3 to AV _{REF} + 0.3 ^{Note 1} and -0.3 to V _{DD} + 0.3 ^{Note 1}	V
Output current, high	Іон	Per pin		-10	mA
		Total for P00 P64 to P67, F	to P03, P40 to P47, P50 to P57, P70 to P75	-15	mA
		Total for P20	to P25, P30 to P36	-15	mA
Output current, low	Іоь		00 to P03, P20 to P25, P34 to P36, P64 to P67, P70 to P75	20	mA
		Per pin for P3	30 to P33, P50 to P57	30	mA
		Total for P00 P70 to P75	to P03, P40 to P47, P64 to P67,	50	mA
		Total for P20	to P25	20	mA
		Total for P30	to P36	100	mA
		Total for P50	to P57	100	mA
Operating ambient temperature	Та	During norma	l operation	-40 to +85	°C
Storage temperature	Tstg			-40 to +125	°C

Notes 1. 6.5 V or below

(Note 2 is explained on the following page.)

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

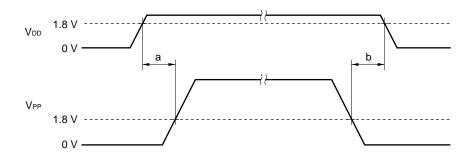
Notes 2. Make sure that the following conditions of the VPP voltage application timing are satisfied when the flash memory is written.

• When supply voltage rises

VPP must exceed VDD 10 μ s or more after VDD has reached the lower-limit value (1.8 V) of the operating voltage range (see a in the figure below).

· When supply voltage drops

VDD must be lowered 10 μ s or more after VPP falls below the lower-limit value (1.8 V) of the operating voltage range of VDD (see b in the figure below).



Capacitance (TA = 25°C, VDD = Vss = 0 V)

Parameter	Symbol	Conditions			TYP.	MAX.	Unit
Input capacitance	Cin	f = 1 MHz Unmeasured pins returned to 0 V.				15	pF
I/O capacitance	Сю	f = 1 MHz Unmeasured pins returned to 0 V.	P00 to P03, P20 to P25, P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75,			15	pF
			P30 to P33			20	pF

Remark Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Ceramic	1 1	Oscillation	4.5 V ≤ V _{DD} ≤ 5.5 V	1.0		12.0	MHz
resonator	VPP X2 X1	frequency (fx)Note 1	3.0 V ≤ V _{DD} < 4.5 V	1.0		8.38	
			1.8 V ≤ V _{DD} < 3.0 V	1.0		5.0	
	C2 = C1=	Oscillation	After V _{DD} reaches			4	ms
		stabilization timeNote 2	oscillation voltage range				
	<i>m</i>		MIN.				
Crystal	V _{PP} X2 X1	Oscillation	4.5 V ≤ V _{DD} ≤ 5.5 V	1.0		12.0	MHz
resonator		frequency (fx)Note 1	3.0 V ≤ V _{DD} < 4.5 V	1.0		8.38	
	→ I□ → C2 = C1 =		1.8 V ≤ V _{DD} < 3.0 V	1.0		5.0	
		Oscillation	4.0 V ≤ V _{DD} ≤ 5.5 V			10	ms
	1777	stabilization timeNote 2	1.8 V ≤ V _{DD} < 4.0 V			30	
External	1 1	X1 input	4.5 V ≤ V _{DD} ≤ 5.5 V	1.0		12.0	MHz
clock	X2 X1	frequency (fx)Note 1	$3.0 \text{ V} \leq \text{V}_{DD} < 4.5 \text{ V}$	1.0		8.38	
			1.8 V ≤ V _{DD} < 3.0 V	1.0		5.0	
		X1 input	$4.5 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	38		500	ns
	Å	high-/low-level width	3.0 V ≤ V _{DD} < 4.5 V	50		500	
	Τ	(txH, txL)	1.8 V ≤ V _{DD} < 3.0 V	85		500	

Main System Clock Oscillator Characteristics (TA = -40 to +85°C, VDD = 1.8 to 5.5 V)

- Notes 1. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.
 - 2. Time required to stabilize oscillation after reset or STOP mode release.
- Cautions 1. When using the main system clock oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.
 - · Keep the wiring length as short as possible.
 - Do not cross the wiring with the other signal lines.
 - Do not route the wiring near a signal line through which a high fluctuating current flows.
 - Always make the ground point of the oscillator capacitor the same potential as Vss1.
 - . Do not ground the capacitor to a ground pattern through which a high current flows.
 - · Do not fetch signals from the oscillator.
 - 2. When the main system clock is stopped and the system is operating on the subsystem clock, wait until the oscillation stabilization time has been secured by the program before switching back to the main system clock.
 - **Remark** For the resonator selection and oscillator constant, customers are required to either evaluate the oscillation themselves or apply to the resonator manufacturer for evaluation.

Subsystem Clock Oscillator Characteristics (TA = -40 to +85°C, VDD = 1.8 to 5.5 V)

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Crystal resonator	XT2 XT1V _{PP}	Oscillation frequency (fxr)Note 1		32	32.768	35	kHz
	C4 - C3	Oscillation	4.0 V ≤ V _{DD} ≤ 5.5 V		1.2	2	s
	·	stabilization timeNote 2	1.8 V ≤ V _{DD} < 4.0 V			10	
External clock	XT2 XT1	X1 input frequency (fxr)Note 1		32		38.5	kHz
	\$	X1 input high-/low-level width (txth, txtl)		12		15	μs

- Notes 1. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.
 - 2. Time required to stabilize oscillation after VDD reaches oscillator voltage MIN.
- Cautions 1. When using the subsystem clock oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.
 - . Keep the wiring length as short as possible.
 - · Do not cross the wiring with the other signal lines.
 - . Do not route the wiring near a signal line through which a high fluctuating current flows.
 - Always make the ground point of the oscillator capacitor to the same potential as Vss1.
 - . Do not ground the capacitor to a ground pattern through which a high current flows.
 - Do not fetch signals from the oscillator.
 - The subsystem clock oscillator is designed as a low-amplitude circuit for reducing power consumption, and is more prone to malfunction due to noise than the main system clock oscillator. Particular care is therefore required with the wiring method when the subsystem clock is used.

Remark For the resonator selection and oscillator constant, customers are required to either evaluate the oscillation themselves or apply to the resonator manufacturer for evaluation.



DC Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 5.5 \text{ V}$)

Parameter	Symbol	Conditions	S	MIN.	TYP.	MAX.	Unit
Output current,	Іон	Per pin				-1	mA
high		All pins				-15	mA
Output current,	loL	Per pin for P00 to P03, P20 to P	25, P34 to P36,			10	mA
low		P40 to P47, P64 to P67, P70 to	P75				
		Per pin for P30 to P33, P50 to P	257			15	mA
		Total for P00 to P03, P40 to P47,	P64 to P67, P70 to P75			20	mA
		Total for P20 to P25				10	mA
		Total for P30 to P36				70	mA
		Total for P50 to P57	T			70	mA
Input voltage,	V _{IH1}	P10 to P17, P21, P24, P35,	$2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	0.7V _{DD}		V _{DD}	V
high		P40 to P47, P50 to P57,	1.8 V ≤ V _{DD} < 2.7 V	0.8V _{DD}		V _{DD}	V
		P64 to P67, P74, P75		0.0133			
	V _{IH2}	P00 to P03, P20, P22, P23, P25,	$2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	0.8V _{DD}		V _{DD}	V
		P34, P36, P70 to P73, RESET	$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	0.85V _{DD}		V _{DD}	V
	VIH3	P30 to P33	2.7 V ≤ V _{DD} ≤ 5.5 V	0.7V _{DD}		5.5	V
		(N-ch open-drain)	1.8 V ≤ V _{DD} < 2.7 V	0.8V _{DD}		5.5	V
	V _{IH4}	X1, X2	2.7 V ≤ V _{DD} ≤ 5.5 V	V _{DD} - 0.5		V _{DD}	V
			1.8 V ≤ V _{DD} < 2.7 V	V _{DD} - 0.2		V _{DD}	V
	V _{IH5}	XT1, XT2	4.0 V ≤ V _{DD} ≤ 5.5 V	0.8V _{DD}		V _{DD}	V
			1.8 V ≤ V _{DD} < 4.0 V	0.9V _{DD}		V _{DD}	V
Input voltage,	V _{IL1}	P10 to P17, P21, P24, P35,	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.3V _{DD}	V
low		P40 to P47, P50 to P57,				2.51/	.,
		P64 to P67, P74, P75	1.8 V ≤ V _{DD} < 2.7 V	0		0.2V _{DD}	V
	V _{IL2}	P00 to P03, P20, P22, P23, P25,	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.2V _{DD}	V
		P34, P36, P70 to P73, RESET	1.8 V ≤ V _{DD} < 2.7 V	0		0.15V _{DD}	V
	V _{IL3}	P30 to P33	4.0 V ≤ V _{DD} ≤ 5.5 V	0		0.3V _{DD}	V
			2.7 V ≤ V _{DD} < 4.0 V	0		0.2VDD	V
			1.8 V ≤ V _{DD} < 2.7 V	0		0.1V _{DD}	V
	VIL4	X1, X2	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.4	V
			$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	0		0.2	V
	V _{IL5}	XT1, XT2	4.0 V ≤ V _{DD} ≤ 5.5 V	0		0.2V _{DD}	V
			1.8 V ≤ V _{DD} < 4.0 V	0		0.1VDD	V
Output voltage,	V _{OH1}	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}, \text{ IoH} = -1 \text{ mA}$	1	V _{DD} - 1.0		V _{DD}	V
high		$1.8 \text{ V} \le \text{V}_{DD} < 4.0 \text{ V}, \text{ Ioh} = -100 $	μΑ	V _{DD} - 0.5		V _{DD}	V
Output voltage,	V _{OL1}	P30 to P33	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V},$			2.0	V
low		P50 to P57	IoL = 15 mA		0.4	2.0	V
		P00 to P03, P20 to P25, P34 to P36,	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$			0.4	V
		P40 to P47, P64 to P67, P70 to P75	IoL = 1.6 mA				
	V _{OL2}	IoL = 400 μA				0.5	V

 $\textbf{Remark} \quad \text{Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.}$

DC Characteristics (T_A = -40 to +85°C, V_{DD} = 1.8 to 5.5 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішн1	V _{IN} = V _{DD} P00 to P03, P10 to P17, P20 to P25, P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75, RESET				3	μΑ
	ILIH2		X1, X2, XT1, XT2			20	μΑ
	Ішнз	Vin = 5.5 V	P30 to P33			3	μΑ
Input leakage current, low	ILIL1	V _{IN} = 0 V	P00 to P03, P10 to P17, P20 to P25, P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75, RESET			-3	μΑ
	ILIL2		X1, X2, XT1, XT2			-20	μΑ
	Ішз		P30 to P33			-3	μΑ
Output leakage current, high	Ісон	Vout = Vdd				3	μΑ
Output leakage current, low	ILOL	Vout = 0 V				-3	μΑ
Software pull- up resistor	R	V _{IN} = 0 V, P00 to P03, P20 to P25, P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75		15	30	90	kΩ

Remark Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.

DC Characteristics (T_A = -40 to +85°C, V_{DD} = 1.8 to 5.5 V)

Parameter	Symbol			MIN.	TYP.	MAX.	Unit	
Power supply current ^{Note 1}	_{DD1} Note 2	12.0 MHz crystal oscillation	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 3}}$	When A/D converter is stopped		16	32	mA
		operating mode		When A/D converter is operating ^{Note 7}		17	34	mA
		8.38 MHz crystal oscillation	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 3}}$	When A/D converter is stopped		10.5	21	mA
		operating mode		When A/D converter is operating ^{Note 7}		11.5	23	mA
			V _{DD} = 3.0 V + 10% ^{Notes 3, 6}	When A/D converter is stopped		7	14	mA
				When A/D converter is operating ^{Note 7}		8	16	mA
		5.00 MHz crystal oscillation	V _{DD} = 3.0 V ±10% ^{Note 3}	When A/D converter is stopped		4.5	9	mA
		operating mode		When A/D converter is operating ^{Note 7}		5.5	11	mA
			-	When A/D converter is stopped		1	2	mA
				When A/D converter is operating Note 7		2	6	mA
	I _{DD2}	12.0 MHz \crystal oscillation		When peripheral functions are stopped		2	4	mA
		HALT mode		When peripheral functions are operating			8	mA
		8.38 MHz crystal oscillation	$V_{DD} = 5.0 \text{ V} \pm 10\%^{\text{Note 3}}$	When peripheral functions are stopped		1.2	2.4	mA
		5.00 MHz crystal oscillation HALT mode		When peripheral functions are operating			5	mA
			$V_{DD} = 3.0 \text{ V} + 10\%^{\text{Notes 3, 6}}$	When peripheral functions are stopped		0.6	1.2	mA
				When peripheral functions are operating			2.4	mA
			V _{DD} = 3.0 V ±10% ^{Note 3}	When peripheral functions are stopped		0.4	0.8	mA
				When peripheral functions are operating			1.7	mA
			V _{DD} = 2.0 V ±10% ^{Note 4}	When peripheral functions are stopped		0.2	0.4	mA
				When peripheral functions are operating			1.1	mA
	IDD3	32.768 kHz crysta	l oscillation	V _{DD} = 5.0 V ±10%		115	230	μΑ
ı		operating mode ^{No}	te 5	V _{DD} = 3.0 V ±10%		95	190	μA
		, , , ,		V _{DD} = 2.0 V ±10%		75	150	μΑ
	I _{DD4}	32.768 kHz crysta	al oscillation	V _{DD} = 5.0 V ±10%		30	60	μA
		HALT mode ^{Note 5}		$V_{DD} = 3.0 \text{ V} \pm 10\%$		6	18	μΑ
				$V_{DD} = 2.0 \text{ V} \pm 10\%$		2	10	μΑ
	I _{DD5}	XT1 = V _{DD} STOP	mode	$V_{DD} = 5.0 \text{ V} \pm 10\%$		0.1	30	μΑ
	1003	When feedback resis		$V_{DD} = 3.0 \text{ V} \pm 10\%$		0.05	10	μΑ
				$V_{DD} = 2.0 \text{ V} \pm 10\%$		0.05	10	μΑ

- **Notes 1.** Total current through the internal power supply (VDD0, VDD1) (except the current through pull-up resistors of ports).
 - 2. IDD1 includes the peripheral operation current.
 - 3. When the processor clock control register (PCC) is set to 00H.
 - 4. When PCC is set to 02H.
 - 5. When main system clock operation is stopped.
 - **6.** The values show the specifications when $V_{DD} = 3.0$ to 3.3 V. The value in the TYP. column show the specifications when $V_{DD} = 3.0$ V.
 - 7. Includes the current through the AVDD pin.



AC Characteristics

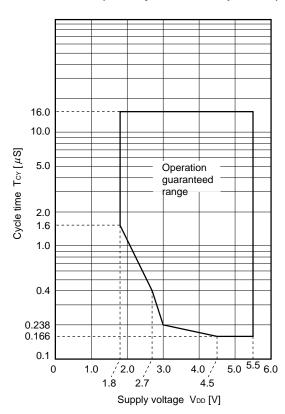
(1) Basic Operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 5.5 \text{ V}$)

Parameter	Symbol	Co	nditions	MIN.	TYP.	MAX.	Unit
Cycle time	Тсч	Operating with	4.5 V ≤ V _{DD} ≤ 5.5 V	0.166		16	μs
(Min. instruction		main system clock	$3.0 \text{ V} \leq \text{V}_{DD} \leq 4.5 \text{ V}$	0.238		16	μs
execution time)			$2.7 \text{ V} \leq \text{V}_{DD} \leq 3.0 \text{ V}$	0.4		16	μs
			1.8 V ≤ V _{DD} ≤ 2.7 V	1.6		16	μs
		Operating with subs	system clock	103.9Note 1	122	125	μs
TI00, TI01 input	ttiho, ttilo	3.0 V ≤ V _{DD} ≤ 5.5 V		2/f _{sam} +0.1 Note 2			μs
high-/low-level		2.7 V ≤ V _{DD} < 3.0 V		2/f _{sam} +0.2 ^{Note} 2			μs
width		1.8 V ≤ V _{DD} < 2.7 V		2/f _{sam} +0.5 ^{Note} 2			μs
TI50, TI51 input	f _{TI5}	2.7 V ≤ V _{DD} ≤ 5.5 V	2.7 V ≤ V _{DD} ≤ 5.5 V			4	MHz
frequency		1.8 V ≤ V _{DD} < 2.7 V		0		275	kHz
TI50, TI51 input	ttihs, ttils	2.7 V ≤ V _{DD} ≤ 5.5 V		100			ns
high-/low-level width		1.8 V ≤ V _{DD} < 2.7 V		1.8			ns
Interrupt request	tinth, tintl	INTP0 to INTP3,	2.7 V ≤ V _{DD} ≤ 5.5 V	1			μs
input high-/low- level width		P40 to P47	1.8 V ≤ V _{DD} < 2.7 V	2			μs
RESET	trsL	2.7 V ≤ V _{DD} ≤ 5.5 V		10			μs
low-level width		1.8 V ≤ V _{DD} < 2.7 V		20			μs

Notes 1. Value when the external clock is used. When a crystal resonator is used, it is 114 μ s (MIN.).

2. Selection of fsam = fx, fx/4, fx/64 is possible using bits 0 and 1 (PRM00, PRM01) of prescaler mode register 0 (PRM0). However, if the Tl00 valid edge is selected as the count clock, the value becomes fsam = fx/8.

Tcy vs. VDD (main system clock operation)



(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 4.0 \text{ to } 5.5 \text{ V}$)

(1/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	t asth		0.3tcy		ns
Address setup time	tads		20		ns
Address hold time	t adh		6		ns
Input time from address to data	tADD1			(2 + 2n)tcy - 54	ns
	tADD2			(3 + 2n)tcy - 60	ns
Output time from $\overline{RD} \downarrow$ to address	trdad		0	100	ns
Input time from RD↓ to data	tRDD1			(2 + 2n)tcy - 87	ns
	tRDD2			(3 + 2n)tcy - 93	ns
Read data hold time	trdh		0		ns
RD low-level width	trdL1		(1.5 + 2n)tcy - 33		ns
	trdl2		(2.5 + 2n)tcy - 33		ns
Input time from $\overline{RD}\downarrow$ to $\overline{WAIT}\downarrow$	trdwT1			tcy - 43	ns
	trdwt2			tcy - 43	ns
Input time from WR↓ to WAIT↓	twrwt			tcy - 25	ns
WAIT low-level width	tw _T L		(0.5 + n)tcy + 10	(2 + 2n)tcy	ns
Write data setup time	twos		60		ns
Write data hold time	twoн		6		ns
WR low-level width	twrL1		(1.5 + 2n)tcy - 15		ns
Delay time from ASTB \downarrow to $\overline{\text{RD}}\downarrow$	tastrd		6		ns
Delay time from ASTB \downarrow to $\overline{\mathrm{WR}} \downarrow$	tastwr		2tcy - 15		ns
Delay time from RD↑ to ASTB↑ in external fetch	trdast		0.8tcy - 15	1.2tcy	ns
Hold time from RD↑ to address in external fetch	trdadh		0.8tcy - 15	1.2tcy + 30	ns
Write data output time from RD↑	trowd		40		ns
Write data output time from $\overline{WR} \downarrow$	twrwd		10	60	ns
Hold time from WR↑ to address	twradh		0.8tcy - 15	1.2tcy + 30	ns
Delay time from WAIT↑ to RD↑	twtrd		0.8tcy	2.5tcy + 25	ns
Delay time from WAIT↑ to WR↑	twrwr		0.8tcy	2.5tcy + 25	ns

Caution Tcy can only be used when the MIN. value is 0.238 μ s.

- 2. n indicates the number of waits.
- 3. $C_L = 100$ pF (C_L is the load capacitance of the AD0 to AD7, A8 to A15, \overline{RD} , \overline{WR} , \overline{WAIT} , and ASTB pins.)

(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 2.7 \text{ to } 4.0 \text{ V}$)

(2/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	t asth		0.3tcy		ns
Address setup time	tads		30		ns
Address hold time	t adh		10		ns
Input time from address to data	t _{ADD1}			(2 + 2n)tcy - 108	ns
	tADD2			(3 + 2n)tcy - 120	ns
Output time from RD↓ to address	trdad		0	200	ns
Input time from RD↓ to data	t _{RDD1}			(2 + 2n)tcy - 148	ns
	tRDD2			(3 + 2n)tcy - 162	ns
Read data hold time	t RDH		0		ns
RD low-level width	trdL1		(1.5 + 2n)tcy - 40		ns
	tRDL2		(2.5 + 2n)tcy - 40		ns
Input time from $\overline{RD} \downarrow$ to $\overline{WAIT} \downarrow$	t RDWT1			tcy - 75	ns
	trdwt2			tcy - 60	ns
Input time from $\overline{\mathrm{WR}}\!\downarrow$ to $\overline{\mathrm{WAIT}}\!\downarrow$	twrwt			tcy - 50	ns
WAIT low-level width	t wTL		(0.5 + 2n)tcy + 10	(2 + 2n)tcy	ns
Write data setup time	twos		60		ns
Write data hold time	twpн		10		ns
WR low-level width	t WRL1		(1.5 + 2n)tcy - 30		ns
Delay time from ASTB \downarrow to $\overline{\text{RD}} \downarrow$	tastrd		10		ns
Delay time from ASTB \downarrow to $\overline{\text{WR}} \downarrow$	t astwr		2tcy - 30		ns
Delay time from $\overline{RD}\!\uparrow$ to ASTB \uparrow in external fetch	trdast		0.8tcy - 30	1.2tcy	ns
Hold time from RD↑ to address in external fetch	trdadh		0.8tcy - 30	1.2tcy + 60	ns
Write data output time from RD↑	trdwd		40		ns
Write data output time from WR↓	twrwd		20	120	ns
Hold time from WR↑ to address	twradh		0.8tcy - 30	1.2tcy + 60	ns
Delay time from WAIT↑ to RD↑	twtrd		0.5tcy	2.5tcy + 50	ns
Delay time from WAIT↑ to WR↑	twtwr		0.5tcy	2.5tcy + 50	ns

Caution Tc γ can only be used when the MIN. value is 0.4 μ s.

- 2. n indicates the number of waits.
- 3. $C_L = 100 \text{ pF}$ (C_L is the load capacitance of the AD0 to AD7, A8 to A15, \overline{RD} , \overline{WR} , \overline{WAIT} , and ASTB pins.)

(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 2.7 \text{ V}$)

(3/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	t asth		0.3tcy		ns
Address setup time	tads		120		ns
Address hold time	tadh		20		ns
Input time from address to data	t _{ADD1}			(2 + 2n)tcy - 233	ns
	tADD2			(3 + 2n)tcy - 240	ns
Output time from RD↓ to address	trdad		0	400	ns
Input time from RD↓ to data	tRDD1			(2 + 2n)tcy - 325	ns
	tRDD2			(3 + 2n)tcy - 332	ns
Read data hold time	t RDH		0		ns
RD low-level width	trdL1		(1.5 + 2n)tcy - 92		ns
	tRDL2		(2.5 + 2n)tcy - 92		ns
Input time from RD↓ to WAIT↓	t RDWT1			tey - 350	ns
	trdwt2			tcy - 132	ns
Input time from WR↓ to WAIT↓	twrwt			tcy - 100	ns
WAIT low-level width	tw⊤∟		(0.5 + 2n)tcy + 10	(2 + 2n)tcy	ns
Write data setup time	twos		60		ns
Write data hold time	twdн		20		ns
WR low-level width	twrL1		(1.5 + 2n)tcy - 60		ns
Delay time from ASTB↓ to RD↓	tastrd		20		ns
Delay time from ASTB↓ to WR↓	tastwr		2tcy - 60		ns
Delay time from RD↑ to ASTB↑ in external fetch	trdast		0.8tcy - 60	1.2tcy	ns
Hold time from RD↑ to address in external fetch	trdadh		0.8tcy - 60	1.2tcy + 120	ns
Write data output time from RD↑	trowd		40		ns
Write data output time from WR↓	twrwd		40	240	ns
Hold time from WR↑ to address	twradh		0.8tcy - 60	1.2tcy + 120	ns
Delay time from WAIT↑ to RD↑	twtrd		0.5tcy	2.5tcy + 100	ns
Delay time from WAIT↑ to WR↑	twtwr		0.5tcy	2.5tcy + 100	ns

Caution Tcy can only be used when the MIN. value is 1.6 μ s.

- 2. n indicates the number of waits.
- 3. $C_L = 100 \text{ pF}$ (C_L is the load capacitance of the AD0 to AD7, A8 to A15, \overline{RD} , \overline{WR} , \overline{WAIT} , and ASTB pins.)

(3) Serial Interface ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 5.5 \text{ V}$)

(a) 3-wire serial I/O mode (SCK3n... Internal clock output)

Parameter	Symbol	Co	nditions	MIN.	TYP.	MAX.	Unit
SCK3n	tkcy1	4.5 V ≤ V _{DD} ≤ 5.5	666			ns	
cycle time		3.0 V ≤ V _{DD} < 4.5	V	954			ns
		2.7 V ≤ V _{DD} < 3.0	V	1600			ns
		1.8 V ≤ V _{DD} < 2.7	V	3200			ns
SCK3n high-/	tkH1, tkL1	3.0 V ≤ V _{DD} ≤ 5.5	V	tксү1/2 – 50			ns
low-level width		1.8 V ≤ V _{DD} < 3.0	V	tксү1/2 – 100			ns
SI3n setup time	tsıĸ1	3.0 V ≤ V _{DD} ≤ 5.5	V	100			ns
(to SCK3n↑)		2.7 V ≤ V _{DD} < 3.0	V	150			ns
		1.8 V ≤ V _{DD} < 2.7	V	300			ns
SI3n hold time	t KSI1	4.5 V ≤ V _{DD} ≤ 5.5	V	300			ns
(from SCK3n↑)		1.8 V ≤ V _{DD} < 4.5	V	400			ns
Delay time from	t KSO1	C = 100 pF ^{Note}	$4.5 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			200	ns
SCK3n↓ to SO3n			1.8 V ≤ V _{DD} < 4.5 V			300	ns
output							

Note C is the load capacitance of the $\overline{SCK3n}$ and SO3n output lines.

(b) 3-wire serial I/O mode (SCK3n... External clock input)

Parameter	Symbol	Co	nditions	MIN.	TYP.	MAX.	Unit
SCK3n	tkcy2	4.5 V ≤ V _{DD} ≤ 5.5	666			ns	
cycle time		3.0 V ≤ V _{DD} < 4.5	V	800			ns
		2.7 V ≤ V _{DD} < 3.0	V	1600			ns
		1.8 V ≤ V _{DD} < 2.7	V	3200			ns
SCK3n high-/	tkH2, tkL2	4.5 V ≤ V _{DD} ≤ 5.5	V	333			ns
low-level width		3.0 V ≤ V _{DD} < 4.5	V	400			ns
		2.7 V ≤ V _{DD} < 3.0	V	800			ns
		1.8 V ≤ V _{DD} < 2.7	V	1600			ns
SI3n setup time	tsık2			100			ns
(to SCK3n↑)							
SI3n hold time	tksi2	4.5 V ≤ V _{DD} ≤ 5.5	V	300			ns
(from SCK3n↑)		1.8 V ≤ V _{DD} < 4.5	V	400			ns
Delay time from	tkso2	C = 100 pF ^{Note}	4.5 V ≤ V _{DD} ≤ 5.5 V			200	ns
SCK3n↓ to SO3n			1.8 V ≤ V _{DD} < 4.5 V			300	ns
output							

Note C is the load capacitance of the SO3n output line.

Remark n = 0, 1

(c) UART mode (dedicated baud-rate generator output)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		$4.5 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			187500	bps
		$3.0 \text{ V} \leq \text{V}_{DD} < 4.5 \text{ V}$			131031	bps
		2.7 V ≤ V _{DD} < 3.0 V			78125	bps
		1.8 V ≤ V _{DD} < 2.7 V			39063	bps

(d) UART mode (external clock input)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
ASCK0 cycle time	tксүз	4.0 V ≤ V _{DD} ≤ 5.5 V	800			ns
		2.7 V ≤ V _{DD} < 4.0 V	1600			ns
		1.8 V ≤ V _{DD} < 2.7 V	3200			ns
ASCK0 high-/low-level width	t кнз,	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	400			ns
	tкLз	$2.7 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}$	800			ns
		1.8 V ≤ V _{DD} < 2.7 V	1600			ns
Transfer rate		$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			39063	bps
		$2.7 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}$			19531	bps
		$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$			9766	bps

(e) UART mode (infrared data transfer mode)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
Transfer rate		$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$		131031	bps
Allowable bit rate error		$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$		±0.87	%
Output pulse width		4.0 V ≤ V _{DD} ≤ 5.5 V	1.2	0.24/fbr ^{Note}	μs
Input pulse width		4.0 V ≤ V _{DD} ≤ 5.5 V	4/fx		μs

Note fbr: Specified baud rate

A/D Converter Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = AV_{DD} = 1.8 \text{ to } 5.5 \text{ V}$, $AV_{SS} = V_{SS} = 0 \text{ V}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution			10	10	10	bit
Overall error Note		4.0 V ≤ AVREF ≤ 5.5 V		±0.2	±0.4	%FSR
		2.7 V ≤ AV _{REF} < 4.0 V		±0.3	±0.6	%FSR
		1.8 V ≤ AV _{REF} < 2.7 V		±0.6	±1.2	%FSR
Conversion time	tconv	4.5 V ≤ AV _{DD} ≤ 5.5 V	12		96	μs
		4.0 V ≤ AVDD < 4.5 V	14		96	μs
		2.7 V ≤ AV _{DD} < 4.0 V	17		96	μs
		1.8 V ≤ AVDD < 2.7 V	28		96	μs
Zero-scale error Notes 1, 2		4.0 V ≤ AV _{REF} ≤ 5.5 V			±0.4	%FSR
		2.7 V ≤ AV _{REF} < 4.0 V			±0.6	%FSR
		1.8 V ≤ AV _{REF} < 2.7 V			±1.2	%FSR
Full-scale errorNotes 1, 2		4.0 V ≤ AV _{REF} ≤ 5.5 V			±0.4	%FSR
		2.7 V ≤ AVREF < 4.0 V			±0.6	%FSR
		1.8 V ≤ AV _{REF} < 2.7 V			±1.2	%FSR
Integral linearity errorNote 1		4.0 V ≤ AV _{REF} ≤ 5.5 V			±2.5	LSB
		2.7 V ≤ AVREF < 4.0 V			±4.5	LSB
		1.8 V ≤ AV _{REF} < 2.7 V			±8.5	LSB
Differential linearity error		4.0 V ≤ AV _{REF} ≤ 5.5 V			±1.5	LSB
		2.7 V ≤ AVREF ≤ 4.0 V			±2.0	LSB
		1.8 V ≤ AVREF < 2.7 V			±3.5	LSB
Analog input voltage	VIAN		0		AVREF	V
Reference voltage	AVREF		1.8		AVDD	V
Resistance between AVREF and AVSS	Rref	During A/D conversion operation	20	40		kΩ

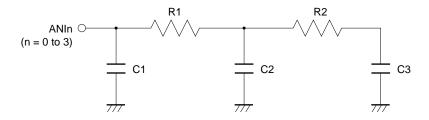
Notes 1. Excluding quantization error (±1/2 LSB).

2. Indicated as a ratio to the full-scale value (%FSR).

Remark When the μ PD78F0034B is used as an 8-bit resolution A/D converter, the specifications are the same as for the μ PD780024A Subseries A/D converter.

Remark The impedance of the analog input pins is shown below.

[Equivalent circuit]



[Parameter value]

					(TYP.)
AV _{DD}	R1	R2	C1	C2	C3
2.7 V	12 kΩ	8.0 kΩ	3.0 pF	3.0 pF	2.0 pF
4.5 V	4 kΩ	2.7 kΩ	3.0 pF	1.4 pF	2.0 pF

Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics (T_A = -40 to +85°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.6		5.5	V
Data retention supply current	Idddr	Subsystem clock stop (XT1 = V _{DD}) and feed-back resistor disconnected		0.1	30	μΑ
Release signal set time	tsrel		0			μs
Oscillation stabilization wait time	twait	Release by RESET		2 ¹⁷ /fx		S
		Release by interrupt request		Note		s

Note Selection of 2^{12} /fx and 2^{14} /fx to 2^{17} /fx is possible using bits 0 to 2 (OSTS0 to OSTS2) of the oscillation stabilization time select register (OSTS).



Flash Memory Programming Characteristics (TA = +10 to +40°C, VDD = 1.8 to 5.5 V, Vss = AVss = 0 V)

(1) Write erase characteristics

Parameter	Symbol		Conditions	3	MIN.	TYP.	MAX.	Unit
Operating frequency	fx	4.5 V ≤ V	$4.5~\textrm{V} \leq \textrm{V}_\textrm{DD} \leq 5.5~\textrm{V}$				10.0	MHz
		3.0 V ≤ V	3.0 V ≤ V _{DD} < 4.5 V		1.0		8.38	MHz
		1.8 V ≤ V	od < 3.0 V		1.0		1.25	MHz
V _{PP} supply voltage	V _{PP2}	During fla	sh memory p	rogramming	9.7	10.0	10.3	V
V _{DD} supply current	IDD	When VPP = VPP2	10 MHz crystal oscillation operating mode	VDD = 5.0 V±10%			30	mA
			8.38 MHz crystal	V _{DD} = 5.0 V±10%			24	mA
			oscillation operating mode	V _{DD} = 3.0 V±10%			17	mA
VPP supply current	IPP	When VPP	= V _{PP2}				100	mA
Step erase time ^{Note 1}	Ter				0.199	0.2	0.201	s
Overall erase time Note 2	Tera	When ste	p erase time	= 0.2 s			20	s/chip
Writeback time ^{Note 3}	Twb				49.4	50	50.6	ms
Number of writebacks per writeback command Note 4	Cwb	When writ	teback time =	50 ms			60	Times
Number of erases/writebacks	Cerwb						16	Times
Step write time Note 5	Twr				48	50	52	μs
Overall write time per word Note 6	Twrw	When step write time = 50 μ s (1 word = 1 byte)			48		520	μs
Number of rewrites per chip ^{Note 7}	Cerwb	1 erase +	1 write after era	ase = 1 rewrite			20	Times

Notes 1. The recommended setting value of the step erase time is 0.2 s.

- 2. The prewrite time before erasure and the erase verify time (writeback time) are not included.
- 3. The recommended setting value of the writeback time is 50 ms.
- **4.** Writeback is executed once by the issuance of the writeback command. Therefore, the number of retries must be the maximum value minus the number of commands issued.
- **5.** The recommended setting value of the step write time is 50 μ s.
- **6.** The actual write time per word is 100 μ s longer. The internal verify time during or after a write is not included.
- When a product is first written after shipment, "erase → write" and "write only" are both taken as one rewrite.

Example: P: Write, E: Erase

Shipped product $\rightarrow P \rightarrow E \rightarrow P \rightarrow E \rightarrow P$: 3 rewrites Shipped product $\rightarrow E \rightarrow P \rightarrow E \rightarrow P \rightarrow E \rightarrow P$: 3 rewrites

(2) Serial write operation characteristics

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V _{PP} set time	tpsron	V _{PP} high voltage	1.0			μs
Set time from V _{DD} ↑ to V _{PP} ↑	t DRPSR	V _{PP} high voltage	10			μs
Set time from V _{PP} ↑ to RESET↑	tpsrrf	V _{PP} high voltage	1.0			μs
V _{PP} count start time from RESET↑	t rfcf		1.0			μs
Count execution time	tcount				2.0	ms
VPP counter high-level width	tсн		8.0			μs
VPP counter low-level width	tcL		8.0			μs
VPP counter noise elimination width	tnfw			40		ns



9.2 μPD78F0034BY, 78F0034BY(A)

Absolute Maximum Ratings (TA = 25°C)

Parameter	Symbol		Conditions	Ratings	Unit
Supply voltage	V _{DD}			-0.3 to +6.5	٧
	V _{PP}	Note 2		-0.3 to +10.5	V
	AV _{DD}			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	AVREF			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	AVss			-0.3 to +0.3	V
Input voltage	VII	,	10 to P17, P20 to P25, P34 to P36, 50 to P57, P64 to P67, P70 to P75, KT2, RESET	-0.3 to V _{DD} + 0.3 ^{Note 1}	V
	V ₁₂	P30 to P33	N-ch open drain	-0.3 to +6.5	V
Output voltage	Vo			-0.3 to V _{DD} + 0.3 ^{Note 1}	V
Analog input voltage	Van	P10 to P17	Analog input pin	AVss -0.3 to AV _{REF} + 0.3 ^{Note 1} and -0.3 to V _{DD} + 0.3 ^{Note 1}	V
Output current, high	Іон	Per pin		-10	mA
		Total for P00 to P03, P40 to P47, P50 to P57, P64 to P67, P70 to P75		-15	mA
		Total for P20	to P25, P30 to P36	-15	mA
Output current, low	loL	Per pin for P00 to P03, P20 to P25, P34 to P36, P40 to P47, P64 to P67, P70 to P75		20	mA
		Per pin for P3	0 to P33, P50 to P57	30	mA
		Total for P00 P70 to P75	to P03, P40 to P47, P64 to P67,	50	mA
		Total for P20	to P25	20	mA
		Total for P30	to P36	100	mA
		Total for P50	to P57	100	mA
Operating ambient temperature	ТА	During normal	operation	-40 to +85	°C
Storage temperature	Tstg			-40 to +125	°C

Notes 1. 6.5 V or below

(Note 2 is explained on the following page.)

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

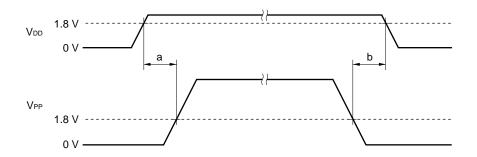
Notes 2. Make sure that the following conditions of the V_{PP} voltage application timing are satisfied when the flash memory is written.

• When supply voltage rises

 V_{PP} must exceed V_{DD} 10 μs or more after V_{DD} has reached the lower-limit value (1.8 V) of the operating voltage range (see a in the figure below).

· When supply voltage drops

V_{DD} must be lowered 10 μ s or more after V_{PP} falls below the lower-limit value (1.8 V) of the operating voltage range of V_{DD} (see b in the figure below).



Capacitance (TA = 25°C, VDD = Vss = 0 V)

Parameter	Symbol	Cor	Conditions			MAX.	Unit
Input capacitance	Cin	f = 1 MHz Unmeasured pins returned			15	pF	
I/O capacitance	Сю	f = 1 MHz Unmeasured pins returned to 0 V.	f = 1 MHz P00 to P03, P20 to P25, P34 to P36, P40 to P47,			15	pF
			P30 to P33			20	pF

Remark Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Ceramic	VPP X2 X1	Oscillation	$4.0~V \leq V_{DD} \leq 5.5~V$	1.0		8.38	MHz
resonator		frequency (fx)Note 1	$1.8~V \leq V_{DD} < 4.0~V$	1.0		5.0	
	1	Oscillation	After V _{DD} reaches			4	ms
	GZ T C17	stabilization timeNote 2	oscillation voltage range				
	7/7		MIN.				
Crystal	V _{PP} X2 X1	Oscillation	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	1.0		8.38	MHz
resonator	+-11	frequency (fx)Note 1	$1.8~V \leq V_{DD} < 4.0~V$	1.0		5.0	
	C2 = C1 =	Oscillation	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			10	ms
	, , , , , , , , , , , , , , , , , , ,	stabilization timeNote 2	$1.8~V \leq V_{DD} < 4.0~V$			30	
External		X1 input	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	1.0		8.38	MHz
clock	X2 X1	frequency (fx)Note 1	$1.8~V \leq V_{DD} < 4.0~V$	1.0		5.0	
		X1 input	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	50		500	ns
	$\stackrel{\downarrow}{\Delta}$	high-/low-level width	$1.8 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}$	85		500	
		(txH, txL)					

Main System Clock Oscillator Characteristics (T_A = −40 to +85°C, V_{DD} = 1.8 to 5.5 V)

Notes 1. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.

- 2. Time required to stabilize oscillation after reset or STOP mode release.
- Cautions 1. When using the main system clock oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.
 - · Keep the wiring length as short as possible.
 - Do not cross the wiring with the other signal lines.
 - . Do not route the wiring near a signal line through which a high fluctuating current flows.
 - Always make the ground point of the oscillator capacitor the same potential as Vss1.
 - Do not ground the capacitor to a ground pattern through which a high current flows.
 - Do not fetch signals from the oscillator.
 - 2. When the main system clock is stopped and the system is operating on the subsystem clock, wait until the oscillation stabilization time has been secured by the program before switching back to the main system clock.

Remark For the resonator selection and oscillator constant, customers are required to either evaluate the oscillation themselves or apply to the resonator manufacture for evaluation.

Subsystem Clock Oscillator Characteristics (TA = -40 to +85°C, VDD = 1.8 to 5.5 V)

Resonator	Recommended Circuit	Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Crystal resonator	XT2 XT1V _{PP}	Oscillation frequency (fxr) ^{Note 1}		32	32.768	35	kHz
	+C4 +C3	Oscillation	4.0 V ≤ V _{DD} ≤ 5.5 V		1.2	2	s
		stabilization time ^{Note 2}	1.8 V ≤ V _{DD} < 4.0 V			10	
External clock	XT2 XT1	X1 input frequency (fxt)Note 1		32		38.5	kHz
		X1 input high-/low-level width (txth, txtl)		12		15	μs

- Notes 1. Indicates only oscillator characteristics. Refer to AC Characteristics for instruction execution time.
 - 2. Time required to stabilize oscillation after VDD reaches oscillator voltage MIN.
- Cautions 1. When using the subsystem clock oscillator, wire as follows in the area enclosed by the broken lines in the above figures to avoid an adverse effect from wiring capacitance.
 - · Keep the wiring length as short as possible.
 - Do not cross the wiring with the other signal lines.
 - . Do not route the wiring near a signal line through which a high fluctuating current flows.
 - Always make the ground point of the oscillator capacitor to the same potential as Vss1.
 - Do not ground the capacitor to a ground pattern through which a high current flows.
 - · Do not fetch signals from the oscillator.
 - The subsystem clock oscillator is designed as a low-amplitude circuit for reducing power consumption, and is more prone to malfunction due to noise than the main system clock oscillator. Particular care is therefore required with the wiring method when the subsystem clock is used.

Remark For the resonator selection and oscillator constant, customers are required to either evaluate the oscillation themselves or apply to the resonator manufacturer for evaluation.



DC Characteristics (T_A = -40 to +85°C, V_{DD} = 1.8 to 5.5 V)

Parameter	Symbol	Conditions	6	MIN.	TYP.	MAX.	Unit
Output current,	Іон	Per pin				-1	mA
high		All pins				-15	mA
Output current,	loL	Per pin for P00 to P03, P20 to P	25, P34 to P36,			10	mA
low		P40 to P47, P64 to P67, P70 to	P75				
		Per pin for P30 to P33, P50 to P	257			15	mA
		Total for P00 to P03, P40 to P47,	P64 to P67, P70 to P75			20	mA
		Total for P20 to P25				10	mA
		Total for P30 to P36				70	mA
		Total for P50 to P57			70	mA	
Input voltage,	V _{IH1}	P10 to P17, P21, P24, P35,	2.7 V ≤ V _{DD} ≤ 5.5 V	0.7V _{DD}		V _{DD}	V
high		P40 to P47, P50 to P57,	1.8 V ≤ V _{DD} < 2.7 V	0.8V _{DD}		V _{DD}	V
		P64 to P67, P74, P75	1.0 V = Vbb < 2.7 V	0.000		V 00	
V _{IH2}	P00 to P03, P20, P22, P23, P25,	2.7 V ≤ V _{DD} ≤ 5.5 V	0.8Vpb		V _{DD}	V	
	P34, P36, P70 to P73, RESET	1.8 V ≤ V _{DD} < 2.7 V	0.85Vpd		V _{DD}	V	
	VIH3	P30 to P33	2.7 V ≤ V _{DD} ≤ 5.5 V	0.7V _{DD}		5.5	V
		(N-ch open-drain)	1.8 V ≤ V _{DD} < 2.7 V	0.8Vpd		5.5	V
	V _{IH4}	X1, X2	2.7 V ≤ V _{DD} ≤ 5.5 V	V _{DD} - 0.5		V _{DD}	V
			1.8 V ≤ V _{DD} < 2.7 V	V _{DD} – 0.2		V _{DD}	V
V _{IH5}		XT1, XT2	4.0 V ≤ V _{DD} ≤ 5.5 V	0.8V _{DD}		V _{DD}	V
		,	1.8 V ≤ V _{DD} < 4.0 V	0.9V _{DD}		V _{DD}	V
Input voltage,	VIL1	P10 to P17, P21, P24, P35,	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.3V _{DD}	V
low		P40 to P47, P50 to P57,					
		P64 to P67, P74, P75	$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$	0		0.2V _{DD}	V
	V _{IL2}	P00 to P03, P20, P22, P23, P25,	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.2V _{DD}	V
		P34, P36, P70 to P73, RESET	1.8 V ≤ V _{DD} < 2.7 V	0		0.15V _{DD}	V
	V _{IL3}	P30 to P33	4.0 V ≤ V _{DD} ≤ 5.5 V	0		0.3V _{DD}	V
			2.7 V ≤ V _{DD} < 4.0 V	0		0.2V _{DD}	V
			1.8 V ≤ V _{DD} < 2.7 V	0		0.1V _{DD}	V
	V _{IL4}	X1, X2	2.7 V ≤ V _{DD} ≤ 5.5 V	0		0.4	V
			1.8 V ≤ V _{DD} < 2.7 V	0		0.2	V
	V _{IL5}	XT1, XT2	4.0 V ≤ V _{DD} ≤ 5.5 V	0		0.2V _{DD}	V
			1.8 V ≤ V _{DD} < 4.0 V	0		0.1V _{DD}	V
Output voltage,	V _{OH1}	4.0 V ≤ V _{DD} ≤ 5.5 V, I _{OH} = −1 mA	`	V _{DD} - 1.0		V _{DD}	V
high		1.8 V ≤ V _{DD} < 4.0 V, I _{OH} = −100 /	иA	V _{DD} - 0.5		V _{DD}	V
Output voltage,	V _{OL1}	P30 to P33	$4.0 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V},$			2.0	V
low		P50 to P57	IoL = 15 mA		0.4	2.0	V
		P00 to P03, P20 to P25, P34 to P36,	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V},$			0.4	V
	P40 to P47, P64 to P67,		IoL = 1.6 mA				
	V _{OL2}	IoL = 400 μA				0.5	V

Remark Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.

DC Characteristics (T_A = -40 to +85°C, V_{DD} = 1.8 to 5.5 V)

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Input leakage current, high	Ішн1	V _{IN} = V _{DD}	P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75, RESET			3	μΑ
	I _{LIH2}		X1, X2, XT1, XT2			20	μΑ
	Інз	VIN = 5.5 V	P30 to P33			3	μΑ
Input leakage current, low	ILIL1	V _{IN} = 0 V	P00 to P03, P10 to P17, P20 to P25, P34 to P36, P40 to P47, P50 to P57, P64 to P67, P70 to P75, RESET			-3	μΑ
	ILIL2		X1, X2, XT1, XT2			-20	μΑ
	ILIL3		P30 to P33			-3	μΑ
Output leakage current, high	Ісон	Vout = Vdd				3	μΑ
Output leakage current, low	ILOL	Vout = 0 V	Vout = 0 V			-3	μΑ
Software pull- up resistor	R	V _{IN} = 0 V, P00 to P03, P20 to P P50 to P57, P64 to P	25, P34 to P36, P40 to P47, 67, P70 to P75	15	30	90	kΩ

Remark Unless otherwise specified, the characteristics of alternate-function pins are the same as those of port pins.

DC Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 5.5 \text{ V}$)

Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
Power supply current ^{Note 1}	_{DD1} Note 2	8.38 MHz crystal oscillation	$V_{DD} = 5.0 \text{ V } \pm 10\%^{\text{Note 3}}$	When A/D converter is stopped		10.5	21	mA
		operating mode		When A/D converter is operating Note 6		11.5	23	mA
		5.00 MHz crystal oscillation operating mode	V _{DD} = 3.0 V ±10% ^{Note 3}	When A/D converter is stopped		4.5	9	mA
				When A/D converter is operating ^{Note 6}		5.5	11	mA
			VDD = 2.0 V ±10%Note 4	When A/D converter is stopped		1	2	mA
				When A/D converter is operating Note 6		2	6	mA
	I _{DD2}	IDD2 8.38 MHz crystal oscillation HALT mode	;	When peripheral functions are stopped		1.2	2.4	mA
				When peripheral functions are operating			5	mA
		5.00 MHz crystal oscillation	V _{DD} = 3.0 V ±10% ^{Note 3}	When peripheral functions are stopped		0.4	0.8	mA
		HALT mode		When peripheral functions are operating			1.7	mA
			V _{DD} = 2.0 V ±10%Note 4	When peripheral functions are stopped		0.2	0.4	mA
				When peripheral functions are operating			1.1	mA
	IDD3	32.768 kHz crys	stal oscillation	V _{DD} = 5.0 V ±10% ^{Note 2}		115	230	μΑ
		operating mode	Note 5	$V_{DD} = 3.0 \text{ V} \pm 10\%^{\text{Note 2}}$		95	190	μΑ
				$V_{DD} = 2.0 \text{ V} \pm 10\%^{\text{Note 3}}$		75	150	μΑ
	I _{DD4}	32.768 kHz crys	stal oscillation	V _{DD} = 5.0 V ±10% ^{Note 2}		30	60	μΑ
		HALT mode ^{Note}	5	V _{DD} = 3.0 V ±10% ^{Note 2}		6	18	μΑ
				V _{DD} = 2.0 V ±10% ^{Note 3}		2	10	μΑ
	I _{DD5}	XT1 = VDD STO	P mode	V _{DD} = 5.0 V ±10% ^{Note 2}		0.1	30	μΑ
		When feedback resistor is not used		V _{DD} = 3.0 V ±10% ^{Note 2}		0.05	10	μΑ
				V _{DD} = 2.0 V ±10% ^{Note 3}		0.05	10	μΑ

Notes 1. Total current through the internal power supply (VDD0, VDD1) (except the current through pull-up resistors of ports).

- 2. IDD1 includes the peripheral operation current.
- 3. When the processor clock control register (PCC) is set to 00H.
- 4. When PCC is set to 02H.
- **5.** When main system clock operation is stopped.
- **6.** Includes the current through the AV_{DD} pin.

AC Characteristics

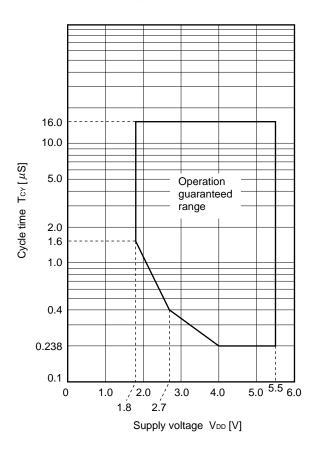
(1) Basic Operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 5.5 \text{ V}$)

Parameter	Symbol	C	onditions		MIN.	TYP.	MAX.	Unit
Cycle time	Тсч	Operating with	4.0 V ≤ V _{DD} ≤ 5.5	5 V	0.238		16	μs
(Min. instruction		main system clock	$2.7 \text{ V} \leq \text{V}_{DD} < 4.0$) V	0.4		16	μs
execution time)			1.8 V ≤ V _{DD} < 2.7 V		1.6		16	μs
		Operating with subsystem clock			103.9Note 1	122	125	μs
TI00, TI01 input	ttiho, ttilo	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			2/f _{sam} +0.1 Note 2			μs
high-/low-level		2.7 V ≤ V _{DD} < 4.0 V			2/f _{sam} +0.2 ^{Note 2}			μs
width		1.8 V ≤ V _{DD} < 2.7 V			2/f _{sam} +0.5 ^{Note 2}			μs
TI50, TI51 input	f T15	$2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	0		4	MHz		
frequency		$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$			0		275	kHz
TI50, TI51 input high-/low-level	ttihs, ttils	$2.7 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			100			ns
width		1.8 V ≤ V _{DD} < 2.7 V			1.8			ns
Interrupt request	tinth, tintl	INTP0 to INTP3,	2.7 V ≤ \	/ _{DD} ≤ 5.5 V	1			μs
input high-/low- level width		P40 to P47	1.8 V ≤ \	/ _{DD} < 2.7 V	2			μs
RESET	trsL	2.7 V ≤ V _{DD} ≤ 5.5 V			10			μs
low-level width		1.8 V ≤ V _{DD} < 2.7 V			20			μs

Notes 1. Value when the external clock is used. When a crystal resonator is used, it is 114 μ s (MIN.).

2. Selection of $f_{sam} = fx$, $f_x/4$, $f_x/64$ is possible using bits 0 and 1 (PRM00, PRM01) of prescaler mode register 0 (PRM0). However, if the TI00 valid edge is selected as the count clock, the value becomes $f_{sam} = f_x/8$.

Tcy vs. VDD (main system clock operation)



(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 4.0 \text{ to } 5.5 \text{ V}$)

(1/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	tasth		0.3tcy		ns
Address setup time	tads		20		ns
Address hold time	tadh		6		ns
Input time from address to data	t _{ADD1}			(2 + 2n)tcy - 54	ns
	tADD2			(3 + 2n)tcy - 60	ns
Output time from RD↓ to address	trdad		0	100	ns
Input time from RD↓ to data	tRDD1			(2 + 2n)tcy - 87	ns
	tRDD2			(3 + 2n)tcy - 93	ns
Read data hold time	t RDH		0		ns
RD low-level width	tRDL1		(1.5 + 2n)tcy - 33		ns
	tRDL2		(2.5 + 2n)tcy - 33		ns
Input time from RD↓ to WAIT↓	trdwt1			tcy - 43	ns
	trdwt2			tcy - 43	ns
Input time from WR↓ to WAIT↓	twrwt			tcy - 25	ns
WAIT low-level width	twtl		(0.5 + n)tcy + 10	(2 + 2n)tcy	ns
Write data setup time	twos		60		ns
Write data hold time	twoh		6		ns
WR low-level width	twrL1		(1.5 + 2n)tcy - 15		ns
Delay time from ASTB↓ to RD↓	tastrd		6		ns
Delay time from ASTB \downarrow to $\overline{\mathrm{WR}} \downarrow$	tastwr		2tcy - 15		ns
Delay time from RD↑ to ASTB↑ in external fetch	trdast		0.8tcy - 15	1.2tcy	ns
Hold time from RD↑ to address in external fetch	trdadh		0.8tcy - 15	1.2tcy + 30	ns
Write data output time from RD↑	trowd		40		ns
Write data output time from WR↓	twrwd		10	60	ns
Hold time from WR↑ to address	twradh		0.8tcy - 15	1.2tcy + 30	ns
Delay time from WAIT↑ to RD↑	twtrd		0.8tcy	2.5tcy + 25	ns
Delay time from WAIT↑ to WR↑	twrwr		0.8tcy	2.5tcy + 25	ns

Caution Tcy can only be used when the MIN. value is 0.238 μ s.

- **2.** n indicates the number of waits.
- 3. $C_L = 100 \text{ pF}$ (C_L is the load capacitance of the AD0 to AD7, A8 to A15, $\overline{\text{RD}}$, $\overline{\text{WR}}$, $\overline{\text{WAIT}}$, and ASTB pins.)

(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 2.7 \text{ to } 4.0 \text{ V}$)

(2/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	tasth		0.3tcy		ns
Address setup time	tads		30		ns
Address hold time	tadh		10		ns
Input time from address to data	t _{ADD1}			(2 + 2n)tcy - 108	ns
	tADD2			(3 + 2n)tcy - 120	ns
Output time from RD	trdad		0	200	ns
Input time from RD↓ to data	tRDD1			(2 + 2n)tcy - 148	ns
	tRDD2			(3 + 2n)tcy - 162	ns
Read data hold time	t RDH		0		ns
RD low-level width	tRDL1		(1.5 + 2n)tcy - 40		ns
	tRDL2		(2.5 + 2n)tcy - 40		ns
Input time from RD↓ to WAIT↓	trdwT1			tcy - 75	ns
	trdwt2			tcy - 60	ns
Input time from $\overline{WR} \downarrow$ to $\overline{WAIT} \downarrow$	twrwt			tcy - 50	ns
WAIT low-level width	twtL		(0.5 + 2n)tcy + 10	(2 + 2n)tcy	ns
Write data setup time	twos		60		ns
Write data hold time	twoH		10		ns
WR low-level width	twrL1		(1.5 + 2n)tcy - 30		ns
Delay time from ASTB↓ to \overline{RD} ↓	tastrd		10		ns
Delay time from ASTB↓ to WR↓	tastwr		2tcy - 30		ns
Delay time from RD↑ to ASTB↑ in external fetch	trdast		0.8tcy - 30	1.2tcy	ns
Hold time from RD↑ to address in external fetch	trdadh		0.8tcy - 30	1.2tcy + 60	ns
Write data output time from RD↑	trdwd		40		ns
Write data output time from WR↓	twrwd		20	120	ns
Hold time from WR↑ to address	twradh		0.8tcy - 30	1.2tcy + 60	ns
Delay time from WAIT↑ to RD↑	twtrd		0.5tcy	2.5tcy + 50	ns
Delay time from WAIT↑ to WR↑	twtwr		0.5tcy	2.5tcy + 50	ns

Caution Tc $_{\rm Y}$ can only be used when the MIN. value is 0.4 μ s.

- **2.** n indicates the number of waits.
- 3. $C_L = 100 \text{ pF}$ (C_L is the load capacitance of the AD0 to AD7, A8 to A15, $\overline{\text{RD}}$, $\overline{\text{WR}}$, $\overline{\text{WAIT}}$, and ASTB pins.)

(2) Read/write operation ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = 1.8 \text{ to } 2.7 \text{ V}$)

(3/3)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
ASTB high-level width	t asth		0.3tcy		ns
Address setup time	tads		120		ns
Address hold time	t adh		20		ns
Input time from address to data	t _{ADD1}			(2 + 2n)tcy - 233	ns
	tADD2			(3 + 2n)tcy - 240	ns
Output time from $\overline{RD} \downarrow$ to address	trdad		0	400	ns
Input time from RD↓ to data	tRDD1			(2 + 2n)tcy - 325	ns
	tRDD2			(3 + 2n)tcy - 332	ns
Read data hold time	t RDH		0		ns
RD low-level width	trdL1		(1.5 + 2n)tcy - 92		ns
	tRDL2		(2.5 + 2n)tcy - 92		ns
Input time from RD↓ to WAIT↓	t RDWT1			tcy - 350	ns
	trdwt2			tcy - 132	ns
Input time from $\overline{WR}\ \downarrow\ to\ \overline{WAIT}\ \downarrow$	twrwt			tcy - 100	ns
WAIT low-level width	t wTL		(0.5 + 2n)tcy + 10	(2 + 2n)tcr	ns
Write data setup time	twos		60		ns
Write data hold time	twdh		20		ns
WR low-level width	t WRL1		(1.5 + 2n)tcy - 60		ns
Delay time from ASTB↓ to RD↓	tastrd		20		ns
Delay time from ASTB \downarrow to $\overline{\text{WR}} \downarrow$	tastwr		2tcy - 60		ns
Delay time from RD↑ to ASTB↑ in external fetch	trdast		0.8tcy - 60	1.2tcy	ns
Hold time from RD↑ to address in external fetch	t RDADH		0.8tcy - 60	1.2tcy + 120	ns
Write data output time from RD↑	trdwd		40		ns
Write data output time from WR↓	twrwd		40	240	ns
Hold time from WR↑ to address	twradh		0.8tcy - 60	1.2tcy + 120	ns
Delay time from WAIT↑ to RD↑	twtrd		0.5tcy	2.5tcy + 100	ns
Delay time from WAIT↑ to WR↑	twrwr		0.5tcy	2.5tcy + 100	ns

Caution Tc γ can only be used when the MIN. value is 1.6 μ s.

- 2. n indicates the number of waits.
- 3. $C_L = 100 \text{ pF}$ (C_L is the load capacitance of the AD0 to AD7, A8 to A15, \overline{RD} , \overline{WR} , \overline{WAIT} , and ASTB pins.)

(3) Serial Interface (T_A = -40 to +85°C, V_{DD} = 1.8 to 5.5 V)

(a) 3-wire serial I/O mode (SCK30... Internal clock output)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SCK30	tkcy1	4.0 V ≤ V _{DD} ≤ 5.5 V	954			ns
cycle time		2.7 V ≤ V _{DD} < 4.0 V	1600			ns
		1.8 V ≤ V _{DD} < 2.7 V	3200			ns
SCK30 high-/	tkH1, tkL1	4.0 V ≤ V _{DD} ≤ 5.5 V	tксү1/2 – 50			ns
low-level width		1.8 V ≤ V _{DD} < 4.0 V	tксү1/2 - 100			ns
SI30 setup time	tsıkı	4.0 V ≤ V _{DD} ≤ 5.5 V	100			ns
(to SCK30↑)		2.7 V ≤ V _{DD} < 4.0 V	150			ns
		1.8 V ≤ V _{DD} < 2.7 V	300			ns
SI3n hold time (from SCK30↑)	tksıı		400			ns
Delay time from SCK30↓ to SO30 output	tkso1	C = 100 pF ^{Note}			300	ns

Note C is the load capacitance of the $\overline{SCK30}$ and SO30 output lines.

(b) 3-wire serial I/O mode (SCK30... External clock input)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
SCK30	tkcy2	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	800			ns
cycle time		2.7 V ≤ V _{DD} < 4.0 V	1600			ns
		1.8 V ≤ V _{DD} < 2.7 V	3200			ns
SCK30 high-/	tkH2, tkL2	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	400			ns
low-level width		2.7 V ≤ V _{DD} < 4.0 V	800			ns
		1.8 V ≤ V _{DD} < 2.7 V	1600			ns
SI30 setup time (to SCK30↑)	tsık2		100			ns
SI30 hold time (from SCK30↑)	tksi2		400			ns
Delay time from SCK30↓ to SO30 output	tkso2	C = 100 pF ^{Note}			300	ns

Note C is the load capacitance of the SO30 output line.

(c) UART mode (dedicated baud-rate generator output)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		$4.0~\textrm{V} \leq \textrm{V}_\textrm{DD} \leq 5.5~\textrm{V}$			131031	bps
		2.7 V ≤ V _{DD} < 4.0 V			78125	bps
		$1.8 \text{ V} \leq \text{V}_{DD} < 2.7 \text{ V}$			39063	bps

(d) UART mode (external clock input)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
ASCK0 cycle time	tксүз	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	800			ns
		2.7 V ≤ V _{DD} < 4.0 V	1600			ns
		1.8 V ≤ V _{DD} < 2.7 V	3200			ns
ASCK0 high-/low-level width	t кнз,	$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$	400			ns
	tкLз	$2.7 \text{ V} \leq \text{V}_{DD} < 4.0 \text{ V}$	800			ns
		1.8 V ≤ V _{DD} < 2.7 V	1600			ns
Transfer rate		$4.0 \text{ V} \leq \text{V}_{DD} \leq 5.5 \text{ V}$			39063	bps
		2.7 V ≤ V _{DD} < 4.0 V			19531	bps
		1.8 V ≤ V _{DD} < 2.7 V			9766	bps

(e) UART mode (infrared data transfer mode)

Parameter	Symbol	Conditions	MIN.	MAX.	Unit
Transfer rate		$4.0~V \leq V_{DD} \leq 5.5~V$		131031	bps
Allowable bit rate error		$4.0~V \leq V_{DD} \leq 5.5~V$		±0.87	%
Output pulse width		$4.0~V \leq V_{DD} \leq 5.5~V$	1.2	0.24/fbr ^{Note}	μs
Input pulse width		$4.0~V \leq V_{DD} \leq 5.5~V$	4/fx		μs

Note fbr: Specified baud rate

(f) I²C bus mode

	Parameter	Symbol	Standa	rd Mode	High-Spe	ed Mode	Unit
			MIN.	MAX.	MIN.	MAX.	
SCL0 clock free	quency	fclk	0	100	0	400	kHz
Bus free time (between stop a	and start condition)	t BUF	4.7	_	1.3	-	μs
Hold time ^{Note 1}		thd:sta	4.0	_	0.6	-	μs
SCL0 clock low	-level width	tLOW	4.7	-	1.3	_	μs
SCL0 clock high	n-level width	tніgн	4.0	-	0.6	-	μs
Start/restart cor	ndition setup time	tsu:sta	4.7	-	0.6	-	μs
Data hold time	CBUS compatible master	thd:dat	5.0	-	-	-	μs
	I ² C bus		O ^{Note 2}	-	O ^{Note 2}	0.9 ^{Note 3}	μs
Data setup time		tsu:dat	250	-	100 ^{Note 4}	_	ns
SDA0 and SCL	0 signal rise time	tr	_	1,000	20 + 0.1Cb ^{Note 5}	300	ns
SDA0 and SCL0 signal fall time		t⊧	_	300	20 + 0.1Cb ^{Note 5}	300	ns
Stop condition s	setup time	tsu:sto	4.0	_	0.6	-	μs
Spike pulse wid	th controlled by input filter	tsp	_	_	0	50	ns
Capacitive load	per each bus line	Cb	_	400	_	400	pF

- **Notes 1.** In the start condition, the first clock pulse is generated after this hold time.
 - 2. To fill in the undefined area of the SCL0 falling edge, it is necessary for the device to internally provide at least 300 ns of hold time for the SDA0 signal (which is V_{IHmin.} of the SCL0 signal).
 - 3. If the device does not extend the SCL0 signal low hold time (tLow), only maximum data hold time thd:dat needs to be fulfilled.
 - **4.** The high-speed mode I²C bus is available in a standard mode I²C bus system. At this time, the conditions described below must be satisfied.
 - If the device does not extend the SCL0 signal low state hold time $t_{\text{SU:DAT}} \geq 250 \text{ ns}$
 - If the device extends the SCL0 signal low state hold time

 Be sure to transmit the next data bit to the SDA0 line before the SCL0 line is released (t_{Rmax.} + t_{SU:DAT} = 1,000 + 250 = 1,250 ns by standard mode I²C bus specification).
 - 5. Cb: Total capacitance per one bus line (unit: pF)

A/D Converter Characteristics ($T_A = -40 \text{ to } +85^{\circ}\text{C}$, $V_{DD} = AV_{DD} = 1.8 \text{ to } 5.5 \text{ V}$, $AV_{SS} = V_{SS} = 0 \text{ V}$)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution			10	10	10	bit
Overall error Note		4.0 V ≤ AV _{REF} ≤ 5.5 V		±0.2	±0.4	%FSR
		2.7 V ≤ AVREF < 4.0 V		±0.3	±0.6	%FSR
		1.8 V ≤ AVREF < 2.7 V		±0.6	±1.2	%FSR
Conversion time	tconv	4.5 V ≤ AV _{DD} ≤ 5.5 V	12		96	μs
		4.0 V ≤ AVDD < 4.5 V	14		96	μs
		2.7 V ≤ AVDD < 4.0 V	17		96	μs
		1.8 V ≤ AVDD < 2.7 V	28		96	μs
Zero-scale error ^{Notes 1, 2}		4.0 V ≤ AV _{REF} ≤ 5.5 V			±0.4	%FSR
		2.7 V ≤ AV _{REF} < 4.0 V			±0.6	%FSR
		1.8 V ≤ AV _{REF} < 2.7 V			±1.2	%FSR
Full-scale error Notes 1, 2		4.0 V ≤ AV _{REF} ≤ 5.5 V			±0.4	%FSR
		2.7 V ≤ AV _{REF} < 4.0 V			±0.6	%FSR
		1.8 V ≤ AV _{REF} < 2.7 V			±1.2	%FSR
Integral linearity error Note 1		4.0 V ≤ AV _{REF} ≤ 5.5 V			±2.5	LSB
		2.7 V ≤ AV _{REF} < 4.0 V			±4.5	LSB
		1.8 V ≤ AVREF < 2.7 V			±8.5	LSB
Differential linearity error		4.0 V ≤ AV _{REF} ≤ 5.5 V			±1.5	LSB
		2.7 V ≤ AV _{REF} ≤ 4.0 V			±2.0	LSB
		1.8 V ≤ AVREF < 2.7 V			±3.5	LSB
Analog input voltage	VIAN		0		AVREF	V
Reference voltage	AVREF		1.8		AVDD	V
Resistance between AVREF and AVss	RREF	During A/D conversion operation	20	40		kΩ

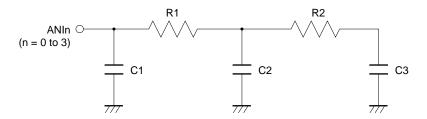
Notes 1. Excluding quantization error (±1/2 LSB).

2. Indicated as a ratio to the full-scale value (%FSR).

Remark When the μ PD78F0034BY is used as an 8-bit resolution A/D converter, the specifications are the same as for the μ PD780024AY Subseries A/D converter.

Remark The impedance of the analog input pins is shown below.

[Equivalent circuit]



[Parameter value]

(TYP.) R1 C1 C2 СЗ $AV_{\text{DD}} \\$ R2 2.7 V 12 k Ω $8.0~k\Omega$ 3.0 pF 3.0 pF 2.0 pF 4.5 V $4~\text{k}\Omega$ $2.7~k\Omega$ 3.0 pF 1.4 pF 2.0 pF

Data Memory STOP Mode Low Supply Voltage Data Retention Characteristics (TA = -40 to +85°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V _{DDDR}		1.6		5.5	٧
Data retention supply current	IDDDR	Subsystem clock stop (XT1 = V _{DD}) and feed-back resistor disconnected		0.1	30	μΑ
Release signal set time	tsrel		0			μs
Oscillation stabilization wait time	twait	Release by RESET	·	2 ¹⁷ /fx		S
		Release by interrupt request		Note		s

Note Selection of 2^{12} /fx and 2^{14} /fx to 2^{17} /fx is possible using bits 0 to 2 (OSTS0 to OSTS2) of the oscillation stabilization time select register (OSTS).



Flash Memory Programming Characteristics (TA = +10 to +40°C, VDD = 1.8 to 5.5 V, Vss = AVss = 0 V)

(1) Write erase characteristics

Parameter	Symbol		Conditions	3	MIN.	TYP.	MAX.	Unit
Operating frequency	fx	4.5 V ≤ V	od ≤ 5.5 V		1.0		10.0	MHz
		3.0 V ≤ V _I	od < 4.5 V		1.0		8.38	MHz
		1.8 V ≤ V	od < 3.0 V		1.0		1.25	MHz
VPP supply voltage	V _{PP2}	During fla	sh memory p	rogramming	9.7	10.0	10.3	V
VDD supply current	IDD	When VPP = VPP2	10 MHz crystal oscillation operating mode	VDD = 5.0 V±10%			30	mA
			8.38 MHz crystal	V _{DD} = 5.0 V±10%			24	mA
			oscillation operating mode	V _{DD} = 3.0 V±10%			17	mA
VPP supply current	IPP	When VPP	= V _{PP2}				100	mA
Step erase time ^{Note 1}	Ter				0.199	0.2	0.201	s
Overall erase time Note 2	Tera	When ste	p erase time	= 0.2 s			20	s/chip
Writeback time ^{Note 3}	Twb				49.4	50	50.6	ms
Number of writebacks per writeback command ^{Note 4}	Cwb	When writ	eback time =	50 ms			60	Times
Number of erases/writebacks	Cerwb						16	Times
Step write time ^{Note 5}	Twr				48	50	52	μs
Overall write time per word ^{Note 6}	Twrw	When step w	rite time = 50 μs	(1 word = 1 byte)	48		520	μs
Number of rewrites per chip ^{Note 7}	Cerwb	1 erase + 1	write after era	ase = 1 rewrite			20	Times

- Notes 1. The recommended setting value of the step erase time is 0.2 s.
 - 2. The prewrite time before erasure and the erase verify time (writeback time) are not included.
 - 3. The recommended setting value of the writeback time is 50 ms.
 - **4.** Writeback is executed once by the issuance of the writeback command. Therefore, the number of retries must be the maximum value minus the number of commands issued.
 - **5.** The recommended setting value of the step write time is 50 μ s.
 - **6.** The actual write time per word is 100 μ s longer. The internal verify time during or after a write is not included.
 - When a product is first written after shipment, "erase → write" and "write only" are both taken as one rewrite.

Example: P: Write, E: Erase

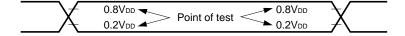
Shipped product $\rightarrow P \rightarrow E \rightarrow P \rightarrow E \rightarrow P$: 3 rewrites Shipped product $\rightarrow E \rightarrow P \rightarrow E \rightarrow P \rightarrow E \rightarrow P$: 3 rewrites

(2) Serial write operation characteristics

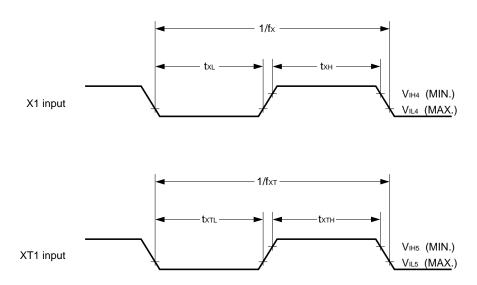
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V _{PP} set time	tpsron	V _{PP} high voltage	1.0			μs
Set time from V _{DD} ↑ to V _{PP} ↑	torpsr	V _{PP} high voltage	10			μs
Set time from V _{PP} ↑ to RESET↑	tpsrrf	V _{PP} high voltage	1.0			μs
V _{PP} count start time from RESET↑	trfcf		1.0			μs
Count execution time	tcount				2.0	ms
VPP counter high-level width	tсн		8.0			μs
VPP counter low-level width	tcL		8.0			μs
VPP counter noise elimination width	tnfw			40		ns

9.3 Timing Chart

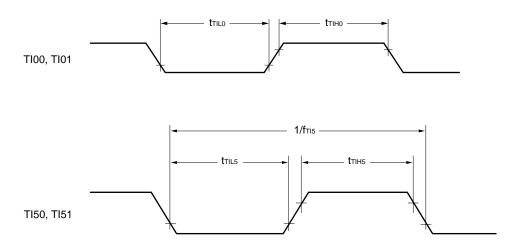
AC Timing Test Point (Excluding X1, XT1 Input)



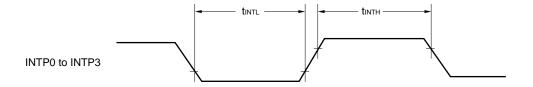
Clock Timing



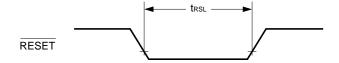
TI Timing



Interrupt Request Input Timing

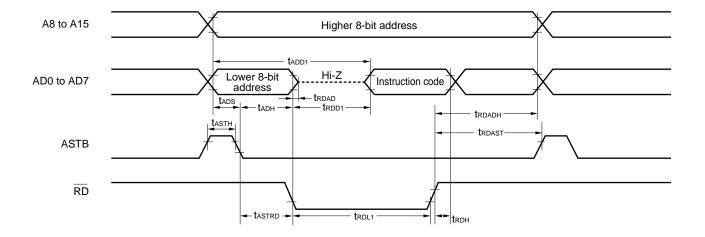


RESET Input Timing

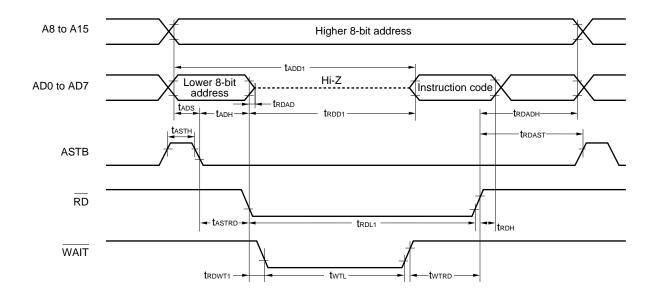


Read/Write Operation

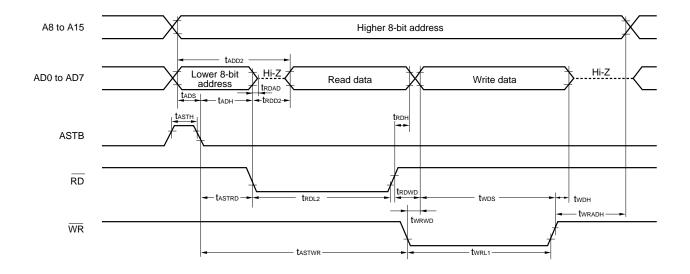
External fetch (no wait):



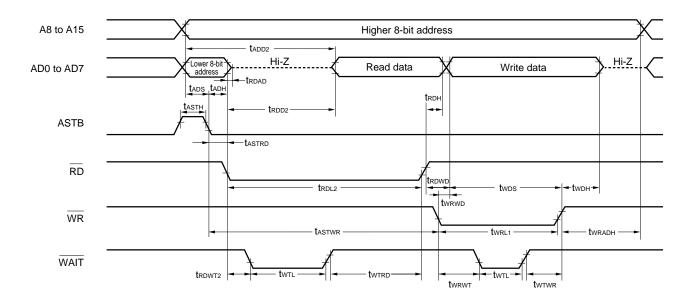
External fetch (wait insertion):



External data access (no wait):

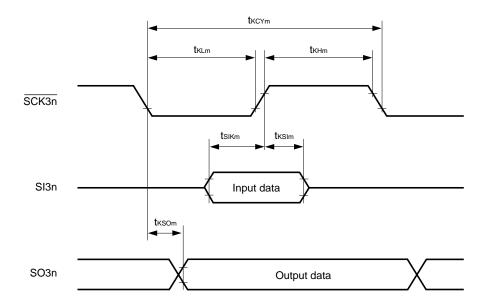


External data access (wait insertion):



Serial Transfer Timing

3-wire serial I/O mode:

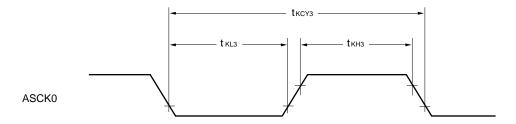


Remarks 1. m = 1, 2

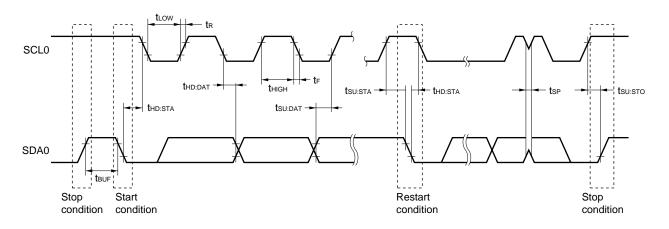
2. μ PD78F0034B and 78F0034B(A): n = 0, 1

3. μ PD78F0034BY and 78F0034BY(A): n = 0

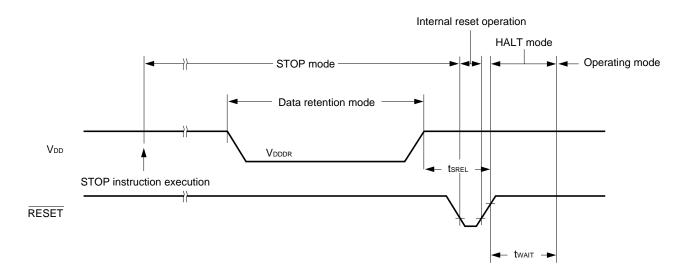
UART mode (external clock input):



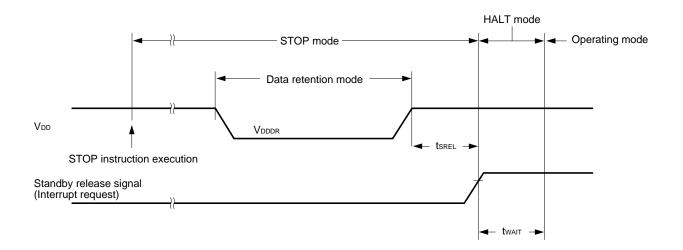
I^2C bus mode (μ PD78F0034BY only):



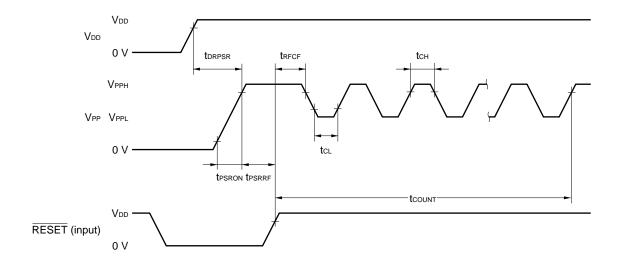
Data Retention Timing (STOP Mode Release by RESET)



Data Retention Timing (Standby Release Signal: STOP Mode Release by Interrupt Request Signal)

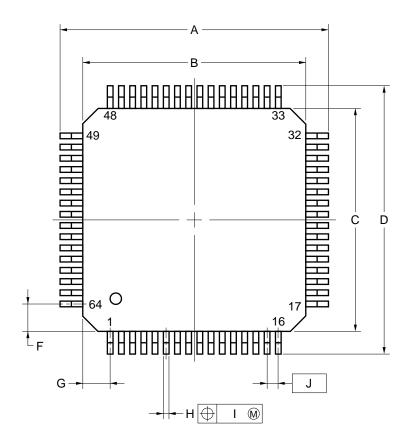


Flash Memory Write Mode Set Timing

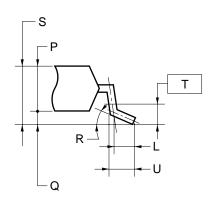


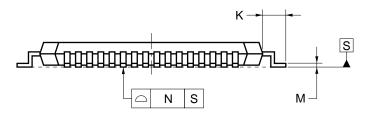
10. PACKAGE DRAWINGS

64-PIN PLASTIC LQFP (10x10)



detail of lead end





NOTE

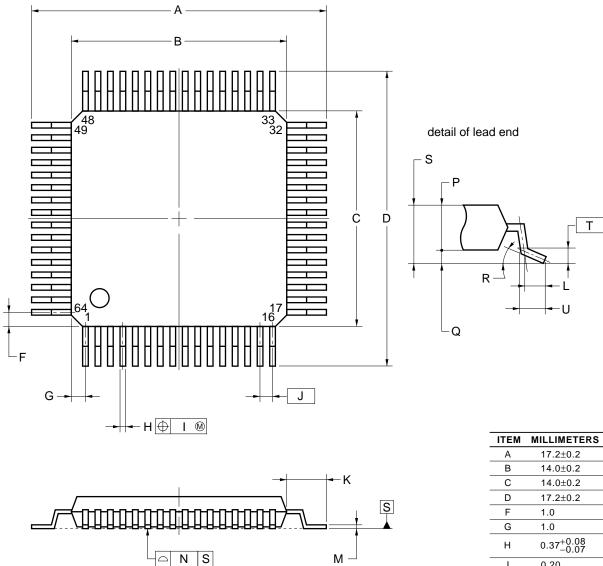
Each lead centerline is located within 0.08 mm of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS
Α	12.0±0.2
В	10.0±0.2
С	10.0±0.2
D	12.0±0.2
F	1.25
G	1.25
Н	0.22±0.05
I	0.08
J	0.5 (T.P.)
K	1.0±0.2
L	0.5
М	$0.17^{+0.03}_{-0.07}$
N	0.08
Р	1.4
Q	0.1±0.05
R	3°+4°
S	1.5±0.10
Т	0.25
U	0.6±0.15
	S64GB-50-8EU-2

S64GB-50-8EU-2

Remark The package and material of ES products are the same as mass produced products.

64-PIN PLASTIC LQFP (14x14)



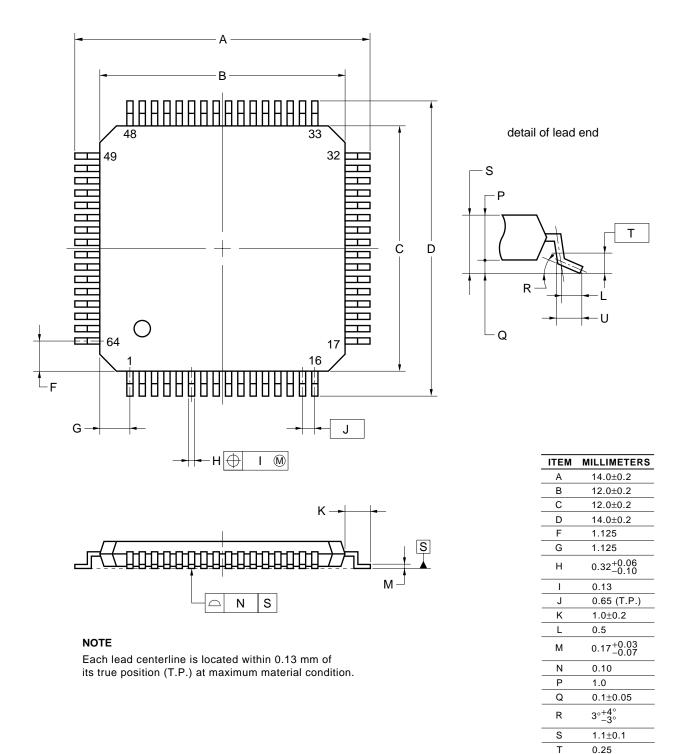
NOTE

Each lead centerline is located within 0.20 mm of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS
Α	17.2±0.2
В	14.0±0.2
С	14.0±0.2
D	17.2±0.2
F	1.0
G	1.0
Н	$0.37^{+0.08}_{-0.07}$
I	0.20
J	0.8 (T.P.)
K	1.6±0.2
L	0.8
М	$0.17^{+0.03}_{-0.06}$
N	0.10
Р	1.4±0.1
Q	0.127±0.075
R	3°+4° -3°
S	1.7 MAX.
Т	0.25
U	0.886±0.15
	P64GC-80-8BS

Remark The package and material of ES products are the same as mass produced products.

64-PIN PLASTIC TQFP (12x12)



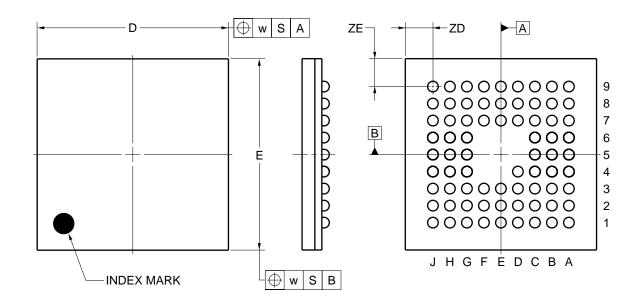
Remark The package and material of ES products are the same as mass produced products.

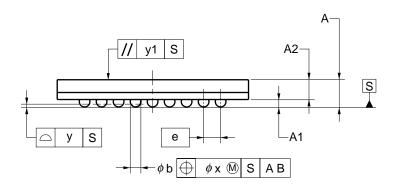
0.6±0.15

P64GK-65-9ET-3

U

73-PIN PLASTIC FBGA (9x9)





	(UNIT:mm)
ITEM	DIMENSIONS
D	9.00±0.10
E	9.00±0.10
w	0.20
Α	1.28±0.10
A1	0.35±0.06
A2	0.93
е	0.80
b	$0.50^{+0.05}_{-0.10}$
X	0.08
у	0.10
y1	0.20
ZD	1.30
ZE	1.30
	P73F1-80-CN3

Remark The external dimensions and materials of the ES version are the same as those of the mass-produced version.

11. RECOMMENDED SOLDERING CONDITIONS

The μ PD78F0034B, 78F0034BY, 78F0034B(A), and 78F0034BY(A) should be soldered and mounted under the following recommended conditions.

For details of the recommended soldering conditions, refer to the document **Semiconductor Device Mounting Technology Manual (C10535E)**.

For soldering methods and conditions other than those recommended below, contact an NEC Electronics sales representative.

Table 11-1. Surface Mounting Type Soldering Conditions (1/2)

(1) μ PD78F0034BGB-8EU: 64-pin plastic LQFP (10 x 10) μ PD78F0034BGB(A)-8EU: 64-pin plastic LQFP (10 x 10) μ PD78F0034BYGB-8EU: 64-pin plastic LQFP (10 x 10) μ PD78F0034BYGB(A)-8EU: 64-pin plastic LQFP (10 x 10)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Package peak temperature: 235°C, Time: 30 seconds max. (at 210°C or higher), Count: Two times or less, Exposure limit: 7 days Note (after 7 days, prebake at 125°C for 10 hours)	IR35-107-2
VPS	Package peak temperature: 215°C, Time: 40 seconds max. (at 200°C or higher), Count: Two times or less, Exposure limit: 7 days Note (after 7 days, prebake at 125°C for 10 hours)	VP15-107-2
Partial heating	Pin temperature: 300°C max., Time: 3 seconds max. (per pin row)	_

Note After opening the dry pack, store it at 25°C or less and 65% RH or less for the allowable storage period.

Caution Do not use different soldering methods together (except for partial heating).

(2) μ PD78F0034BGC-8BS: 64-pin plastic LQFP (14 x 14) μ PD78F0034BGC(A)-8BS: 64-pin plastic LQFP (14 x 14) μ PD78F0034BYGC-8BS: 64-pin plastic LQFP (14 x 14) μ PD78F0034BYGC(A)-8BS: 64-pin plastic LQFP (14 x 14)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Package peak temperature: 235°C, Time: 30 seconds max. (at 210°C or higher), Count: Two times or less	IR35-00-2
VPS	Package peak temperature: 215°C, Time: 40 seconds max. (at 200°C or higher), Count: Two times or less	VP15-00-2
Wave soldering	Solder bath temperature: 260°C max., Time: 10 seconds max., Count: Once, Preheating temperature: 120°C max. (package surface temperature)	WS60-00-1
Partial heating	Pin temperature: 300°C max., Time: 3 seconds max. (per pin row)	-

Caution Do not use different soldering methods together (except for partial heating).

Table 11-1. Surface Mounting Type Soldering Conditions (2/2)

(3) μ PD78F0034BGK-9ET: 64-pin plastic TQFP (12 x 12) μ PD78F0034BGK(A)-9ET: 64-pin plastic TQFP (12 x 12) μ PD78F0034BYGK-9ET: 64-pin plastic TQFP (12 x 12) μ PD78F0034BYGK(A)-9ET: 64-pin plastic TQFP (12 x 12)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Package peak temperature: 235°C, Time: 30 seconds max. (at 210°C or higher), Count: Two times or less, Exposure limit: 7 days ^{Note} (after 7 days, prebake at 125°C for 10 hours)	IR35-107-2
VPS	Package peak temperature: 215°C, Time: 40 seconds max. (at 200°C or higher), Count: Two times or less, Exposure limit: 7 days ^{Note} (after 7 days, prebake at 125°C for 10 hours)	VP15-107-2
Wave soldering	Solder bath temperature: 260°C max., Time: 10 seconds max., Count: Once, Preheating temperature: 120°C max. (package surface temperature), Exposure limit: 7 days Note (after 7 days, prebake at 125°C for 10 hours)	WS60-107-1
Partial heating	Pin temperature: 300°C max., Time: 3 seconds max. (per pin row)	-

Note After opening the dry pack, store it at 25°C or less and 65% RH or less for the allowable storage period.

Caution Do not use different soldering methods together (except for partial heating).

(4) μ PD78F0034BF1-CN3: 73-pin plastic FBGA (9 x 9) μ PD78F0034BYF1-CN3: 73-pin plastic FBGA (9 x 9)

Soldering Method	Soldering Conditions	Recommended ConditionSymbol
Infrared reflow	Package peak temperature: 260°C, Time: 60 seconds max. (at 220°C or higher), Count: Three times or less, Exposure limit: 3 days ^{Note} (after that, prebake at 125°C for 20 hours)	IR60-203-3
VPS	Package peak temperature: 215°C, Time: 40 seconds max. (at 200°C or higher), Count: Three times or less, Exposure limit: 3 days ^{Note} (after that, prebake at 125°C for 20 hours)	VP15-203-3

Note After opening the dry pack, store it at 25°C or less and 65%RH or less for the allowable storage period.

Caution Do not use different soldering methods together.

APPENDIX A. DEVELOPMENT TOOLS

The following development tools are available for system development using the μ PD780034B, 780034BY. Also refer to **(6) Cautions on Using Development Tools.**

(1) Software Package

SP78K0	CD-ROM in which various software tools for 78K/0 development are integrated in one	
	package	

(2) Language Processing Software

RA78K0	Assembler package common to 78K/0 Series	
CC78K0	C compiler package common to 78K/0 Series	
DF780034	Device file for μPD780034A, 780034AY Subseries	
CC78K0-L	C compiler library source file common to 78K/0 Series	

(3) Flash Memory Writing Tools

Flashpro III (FL-PR3, PG-FP3)	Flash programmer dedicated to microcontrollers with on-chip flash memory	
Flashpro IV (FL-PR4, PG-FP4)		
FA-64GB-8EU	Adapter for flash memory writing used connected to the Flashpro III/Flashpro IV.	
FA-64GC-8BS-A	• FA-64GB-8EU: 64-pin plastic LQFP (GB-8EU type)	
FA-64GK-9ET	FA-64GC-8BS-A: 64-pin plastic LQFP (GC-8BS type)	
FA-73F1-CN3-A	• FA-64GK-9ET: 64-pin plastic TQFP (GK-9ET type)	
	• FA-73F1-CN3-A: 73-pin plastic FBGA (F1-CN3 type)	

(4) Debugging Tools

• When using in-circuit emulator IE-78K0-NS

IE-78K0-NS	In-circuit emulator common to 78K/0 Series	
IE-70000-MC-PS-B	Power supply unit for IE-78K0-NS	
IE-78K0-NS-PA	Performance board to enhance and expand the functions of IE-78K0-NS	
IE-70000-98-IF-C	Adapter required when using PC-9800 series as host machine (excluding notebook PCs) (C bus supported)	
IE-70000-CD-IF-A	PC card and interface cable when using notebook PC as host machine (PCMCIA socket supported)	
IE-70000-PC-IF-C	Adapter required when using IBM PC/AT TM or compatible as host machine (ISA bus supported)	
IE-70000-PCI-IF-A	Adapter required when using PC in which PCI bus is incorporated as host machine	
IE-780034-NS-EM1	Emulation board to emulate μ PD780034A, 780034AY Subseries	
NP-64GC	Emulation probe for 64-pin plastic LQFP (GC-8BS type)	
NP-64GC-TQ		
NP-H64GC-TQ		
NP-64GK	Emulation probe for 64-pin plastic TQFP (GK-9ET type)	
NP-H64GK-TQ		
NP-H64GB-TQ	Emulation probe for 64-pin plastic LQFP (GB-8EU type)	
NP-73F1-CN3 ^{Note}	Emulation probe for 73-pin plastic FBGA (F1-CN3 type)	
EV-9200GC-64	Conversion socket to connect the NP64GC and a target system board on which a 64-pin plastic LQFP (GC-8BS type) can be mounted.	
TGC-064SAP	Conversion adapter to connect the NP-64GC-TQ or NP-H64GC-TQ and a target system board on which a 64-pin plastic LQFP (GC-8BS type) can be mounted	
TGK-064SBW	Conversion adapter to connect the NP-64GK or NP-H64GK-TQ and a target system on which a 64-pin plastic TQFP (GK-9ET type) can be mounted	
TGB-064SDP	Conversion socket to connect the NP-H64GB-TQ and a target system board on which a 64-pin plastic LQFP (GB-8EU type) can be mounted	
CSICE73A0909N01,	Conversion socket to connect the NP-73F1-CN3 and a target system board on which a 73-pin plastic	
LSPACK73A0909N01,	FBGA (F1-CN3 type) can be mounted	
CSSOCKET73A0909N01		
ID78K0-NS	Integrated debugger for IE-78K0-NS	
SM78K0	System simulator common to 78K/0 Series	
DF780034	Device file for μPD780034A, 780034AY Subseries	

Note The conversion socket (CSICE73A0909N01, LSPACK73A0909N01, or CSSOCKET73A0909N01) is supplied with the emulation probe (NP-73F1-CN3).

• When using in-circuit emulator IE-78001-R-A

IE-78001-R-A	In-circuit emulator common to 78K/0 Series	
IE-70000-98-IF-C	Adapter required when using PC-9800 series as host machine (excluding notebook PCs) (C bus supported)	
IE-70000-PC-IF-C	Interface adapter when using IBM PC/AT or compatible as host machine (ISA bus supported)	
IE-70000-PCI-IF-A	Adapter required when using PC in which PCI bus is incorporated as host machine	
IE-780034-NS-EM1	Emulation board to emulate μPD780034A, 780034AY Subseries	
IE-78K0-R-EX1	Emulation probe conversion board necessary when using IE-780034-NS-EM1 on IE-78001-R-A	
EP-78240GC-R	Emulation probe for 64-pin plastic LQFP (GC-8BS type)	
EP-78012GK-R	Emulation probe for 64-pin plastic TQFP (GK-9ET type)	
EV-9200GC-64	Conversion socket to connect the EP-78240GC-R and a target system board on which a 64-pin plastic LQFP (GC-8BS type) can be mounted	
TGK-064SBW	Conversion adapter to connect the EP-78012GK-R and a target system board on which a 64-pin plastic TQFP (GK-9ET type) can be mounted	
ID78K0	Integrated debugger for IE-78001-R-A	
SM78K0	System simulator common to 78K/0 Series	
DF780034	Device file for μPD780034A, 780034AY Subseries	

(5) Real-Time OS

RX78K0	Real-time OS for 78K/0 Series
--------	-------------------------------

Caution The 64-pin plastic LQFP (GB-8EU type) and 73-pin plastic FBGA (F1-CN3 type) do not support the IE-78001-R-A.

(6) Cautions on Using Development Tools

- The ID78K0-NS, ID78K0, and SM78K0 are used in combination with the DF780034.
- The CC78K0 and RX78K0 are used in combination with the RA78K0 and the DF780034.
- FL-PR3, FL-PR4, FA-64GC-8BS-A, FA-64GB-8EU, FA-64GK-9ET, FA-73F1-CN3-A, NP-64GC, NP-64GC-TQ, NP-H64GC-TQ, NP-H64GK-TQ, NP-H64GB-TQ, and NP-73F1-CN3 are products made by Naito Densei Machida Mfg. Co., Ltd. (+81-45-475-4191).
- TGC-064SAP, TGK-064SBW, TGB-064SDP, CSICE73A0909N01, LSPACK73A0909N01, and CSSOCKET73A0909N01 are products made by TOKYO ELETECH CORPORATION.

Contact: Daimaru Kogyo, Ltd.

Tokyo Electronic Division (+81-3-3820-7112) Osaka Electronic Division (+81-6-6244-6672)

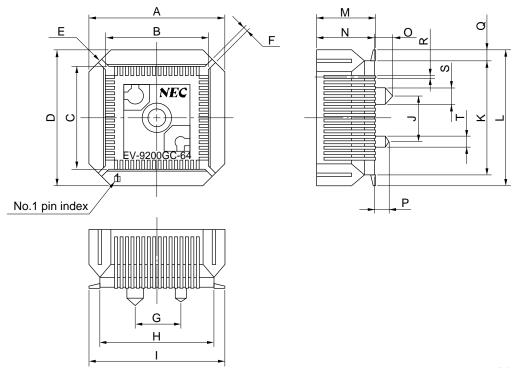
- For third-party development tools, see the **Single-chip Microcontroller Development Tool Selection Guide** (U11069E).
- The host machines and OSs supporting each software are as follows.

Host Machine	PC	EWS
[OS]	PC-9800 series [Japanese Windows™] IBM PC/AT and compatibles	HP9000 series 700™ [HP-UX™] SPARCstation™ [SunOS™, Solaris™]
Software	[Japanese/English Windows]	
RA78K0	√ Note	√
CC78K0	√ Note	$\sqrt{}$
ID78K0-NS	V	_
ID78K0	V	_
SM78K0	V	_
RX78K0	Note	V

Note DOS-based software

Conversion Socket Drawing (EV-9200GC-64) and Footprints

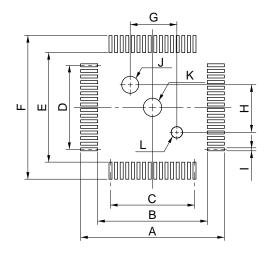
Figure A-1. EV-9200GC-64 Drawing (For Reference Only)



EV-9200GC-64-G0

ITEM	MILLIMETERS	INCHES
Α	18.8	0.74
В	14.1	0.555
С	14.1	0.555
D	18.8	0.74
Е	4-C 3.0	4-C 0.118
F	0.8	0.031
G	6.0	0.236
Н	15.8	0.622
I	18.5	0.728
J	6.0	0.236
K	15.8	0.622
L	18.5	0.728
М	8.0	0.315
N	7.8	0.307
0	2.5	0.098
Р	2.0	0.079
Q	1.35	0.053
R	0.35±0.1	$0.014^{+0.004}_{-0.005}$
S	φ2.3	φ0.091
Т	ø1.5	φ0.059

Figure A-2. EV-9200GC-64 Footprints (For Reference Only)



EV-9200GC-64-P1E

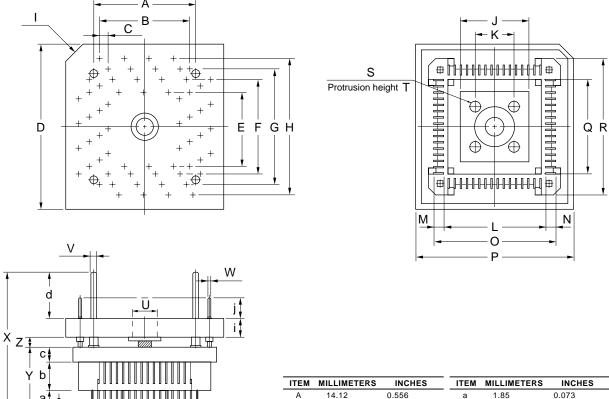
		11101170
ITEM	MILLIMETERS	INCHES
Α	19.5	0.768
В	14.8	0.583
С	0.8±0.02 × 15=12.0±0.05	$0.031^{+0.002}_{-0.001} \times 0.591 = 0.472^{+0.003}_{-0.002}$
D	0.8±0.02 × 15=12.0±0.05	$0.031^{+0.002}_{-0.001} \times 0.591 = 0.472^{+0.003}_{-0.002}$
Е	14.8	0.583
F	19.5	0.768
G	6.00±0.08	$0.236^{+0.004}_{-0.003}$
Н	6.00±0.08	$0.236^{+0.004}_{-0.003}$
I	0.5±0.02	$0.197^{+0.001}_{-0.002}$
J	φ2.36±0.03	$\phi_{0.093^{+0.001}_{-0.002}}$
K	φ2.2±0.1	$\phi_{0.087^{+0.004}_{-0.005}}$
L	φ1.57±0.03	$\phi_{0.062^{+0.001}_{-0.002}}$

Caution

DimensionsofmountpadforEV-9200andthatfortargetdevice (QFP) may be different in some parts. For the recommended mountpad dimensions for QFP, refer to "SEMICONDUCTOR DEVICE MOUNTING TECHNOLOGY MANUAL" (C10535E).

Conversion Adapter Drawing (TGC-064SAP)

Figure A-3. TGC-064SAP Drawing (For Reference Only)



h

ITEM	MILLIMETERS	INCHES
Α	14.12	0.556
В	0.8x15=12.0	0.031x0.591=0.472
С	0.8	0.031
D	20.65	0.813
Е	10.0	0.394
F	12.4	0.488
G	14.8	0.583
Н	17.2	0.677
I	C 2.0	C 0.079
J	9.05	0.356
K	5.0	0.197
L	13.35	0.526
М	1.325	0.052
N	1.325	0.052
0	16.0	0.630
Р	20.65	0.813
Q	12.5	0.492
R	17.5	0.689
S	$4-\phi 1.3$	$4-\phi 0.051$
Т	1.8	0.071
U	ϕ 3.55	ϕ 0.140
V	ϕ 0.9	ϕ 0.035
W	φ0.3	ϕ 0.012
Х	(19.65)	(0.667)
Υ	7.35	0.289
7	1.2	0.047

0.106 TGC-064SAP-G0E

0.138

0.079

0.236

0.010

0.047

0.047

3.5

2.0

6.0

0.25

13.6

1.2

2.4

b c

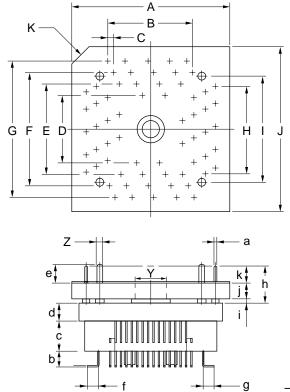
d

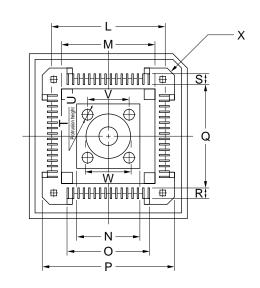
note: Product by TOKYO ELETECH CORPORATION.

e g

Conversion Adapter Drawing (TGK-064SBW)

Figure A-4. TGK-064SBW Drawing (For Reference Only) (Unit: mm)





MILLIMETERS	INCHES
18.4	0.724
0.65x15=9.75	0.026x0.591=0.384
0.65	0.026
7.75	0.305
10.15	0.400
12.55	0.494
14.95	0.589
0.65x15=9.75	0.026x0.591=0.384
11.85	0.467
18.4	0.724
C 2.0	C 0.079
12.45	0.490
10.25	0.404
7.7	0.303
10.02	0.394
14.92	0.587
11.1	0.437
1.45	0.057
1.45	0.057
4- <i>\phi</i> 1.3	4-φ0.051
1.8	0.071
	0.65x15=9.75 0.65 7.75 10.15 12.55 14.95 0.65x15=9.75 11.85 18.4 C 2.0 12.45 10.25 7.7 10.02 14.92 11.1 1.45 1.45 4-\$\psi 1.3

0.197

φ0.209

φ0.140 φ0.035

4-C 0.039

5.0

φ5.3

4-C 1.0

 ϕ 3.55

 ϕ 0.9

_	ITEM	MILLIMETERS	INCHES
	а	φ0.3	φ0.012
1	b	1.85	0.073
	С	3.5	0.138
	d	2.0	0.079
	е	3.9	0.154
	f	1.325	0.052
	g	1.325	0.052
1	h	5.9	0.232
	i	0.8	0.031
_	j	2.4	0.094
	k	2.7	0.106
			TCK 064SBW C1E

TGK-064SBW-G1E

note: Product by TOKYO ELETECH CORPORATION.

APPENDIX B. RELATED DOCUMENTS

The related documents indicated in this publication may include preliminary versions. However, preliminary versions are not marked as such.

Documents Related to Devices

Document Name	Document No.
μPD780024A, 780034A, 780024AY, 780034AY Subseries User's Manual	U14046E
μ PD780021A, 780022A, 780023A, 780024A, 780021AY, 780022AY, 780023AY, 780024AY Data Sheet	U14042E
μPD780021A(A), 780022A(A), 780023A(A), 780024A(A), 780021AY(A), 780022AY(A), 780023AY(A),	U15131E
780024AY(A) Data Sheet	
μ PD780031A, 780032A, 780033A, 780034A, 780031AY, 780032AY, 780033AY, 780034AY Data Sheet	U14044E
μPD780031A(A), 780032A(A), 780033A(A), 780034A(A), 780031AY(A), 780032AY(A), 780033AY(A),	U15132E
780034AY(A) Data Sheet	
μPD78F0034A, 78F0034AY Data Sheet	U14040E
μPD78F0034B, 78F0034BY, 78F0034B(A), 78F0034BY(A) Data Sheet	This document
78K/0 Series User's Manual Instruction	U12326E

Documents Related to Development Software Tools (User's Manuals)

Document Name		Document No.
RA78K0 Assembler Package	Operation	U14445E
	Language	U14446E
	Structured Assembly Language	U11789E
CC78K0 C Compiler	Operation	U14297E
	Language	U14298E
SM78K Series System Simulator Ver. 2.30 or Later	Operation (Windows Based)	U15373E
	External Part User Open Interface Specifications	U15802E
ID78K Series Integrated Debugger Ver. 2.30 or Later	Operation (Windows Based)	U15185E
RX78K0 Real-time OS	Fundamentals	U11537E
	Installation	U11536E
Project Manager Ver. 3.12 or Later (Windows Based)		U14610E

Caution The related documents listed above are subject to change without notice. Be sure to use the latest version of each document for designing.



Documents Related to Development Hardware Tools (User's Manuals)

Document Name	Document No.
IE-78K0-NS In-Circuit Emulator	U13731E
IE-78K0-NS-A In-Circuit Emulator	U14889E
IE-780034-NS-EM1 Emulation Board	U14642E
IE-78001-R-A In-Circuit Emulator	U14142E
IE-78K0-R-EX1 In-Circuit Emulator	To be prepared

Documents Related to Flash Memory Writing

Document Name	Document No.
PG-FP3 Flash Memory Programmer User's Manual	U13502E
PG-FP4 Flash Memory Programmer User's Manual	U15260E

Other Related Documents

Document Name	Document No.
SEMICONDUCTORS SELECTION GUIDE - Products & Packages -	X13769E
Semiconductor Device Mounting Technology Manual	C10535E
Quality Grades on NEC Semiconductor Devices	C11531E
NEC Semiconductor Device Reliability/Quality Control System	C10983E
Guide to Prevent Damage for Semiconductor Devices by Electrostatic Discharge (ESD)	C11892E

Caution The related documents listed above are subject to change without notice. Be sure to use the latest version of each document for designing.



[MEMO]

NOTES FOR CMOS DEVICES -

(1) PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

(2) HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

(3) STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Note: Purchase of NEC Electronics I²C components conveys a license under the Philips I²C Patent Rights to use these components in an I²C system, provided that the system conforms to the I²C Standard Specification as defined by Philips.

FIP and IEBus are trademarks of NEC Electronics Corporation.

Windows is either a registered trademark or trademark of Microsoft Corporation in the United States and/or other countries.

PC/AT is a trademark of International Business Machines Corporation.

HP9000 series 700 and HP-UX are trademarks of Hewlett-Packard Company.

SPARCstation is a trademark of SPARC International, Inc.

Solaris and SunOS are trademarks of Sun Microsystems, Inc.

Regional Information

Some information contained in this document may vary from country to country. Before using any NEC Electronics product in your application, please contact the NEC Electronics office in your country to obtain a list of authorized representatives and distributors. They will verify:

- Device availability
- Ordering information
- Product release schedule
- Availability of related technical literature
- Development environment specifications (for example, specifications for third-party tools and components, host computers, power plugs, AC supply voltages, and so forth)
- Network requirements

In addition, trademarks, registered trademarks, export restrictions, and other legal issues may also vary from country to country.

NEC Electronics America, Inc. (U.S.) • Filiale Italiana

Santa Clara, California Tel: 408-588-6000 800-366-9782 Fax: 408-588-6130 800-729-9288

NEC Electronics (Europe) GmbH

Duesseldorf, Germany Tel: 0211-65 03 01 Fax: 0211-65 03 327

Sucursal en España

Madrid, Spain Tel: 091-504 27 87 Fax: 091-504 28 60

Succursale Française

Vélizy-Villacoublay, France Tel: 01-30-67 58 00 Fax: 01-30-67 58 99

Milano, Italy Tel: 02-66 75 41 Fax: 02-66 75 42 99

• Branch The Netherlands

Eindhoven, The Netherlands Tel: 040-244 58 45 Fax: 040-244 45 80

Tyskland Filial

Taeby, Sweden Tel: 08-63 80 820 Fax: 08-63 80 388

• United Kingdom Branch

Milton Keynes, UK Tel: 01908-691-133 Fax: 01908-670-290

NEC Electronics Hong Kong Ltd.

Hong Kong Tel: 2886-9318 Fax: 2886-9022/9044

NEC Electronics Hong Kong Ltd.

Seoul Branch Seoul, Korea Tel: 02-528-0303 Fax: 02-528-4411

NEC Electronics Shanghai, Ltd.

Shanghai, P.R. China Tel: 021-6841-1138 Fax: 021-6841-1137

NEC Electronics Taiwan Ltd.

Taipei, Taiwan Tel: 02-2719-2377 Fax: 02-2719-5951

NEC Electronics Singapore Pte. Ltd.

Novena Square, Singapore

Tel: 6253-8311 Fax: 6250-3583

- The information in this document is current as of September, 2002. The information is subject to change without notice. For actual design-in, refer to the latest publications of NEC Electronics data sheets or data books, etc., for the most up-to-date specifications of NEC Electronics products. Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.
- No part of this document may be copied or reproduced in any form or by any means without the prior
 written consent of NEC Electronics. NEC Electronics assumes no responsibility for any errors that may
 appear in this document.
- NEC Electronics does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from the use of NEC Electronics products listed in this document or any other liability arising from the use of such products. No license, express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC Electronics or others.
- Descriptions of circuits, software and other related information in this document are provided for illustrative purposes in semiconductor product operation and application examples. The incorporation of these circuits, software and information in the design of a customer's equipment shall be done under the full responsibility of the customer. NEC Electronics assumes no responsibility for any losses incurred by customers or third parties arising from the use of these circuits, software and information.
- While NEC Electronics endeavors to enhance the quality, reliability and safety of NEC Electronics products, customers agree and acknowledge that the possibility of defects thereof cannot be eliminated entirely. To minimize risks of damage to property or injury (including death) to persons arising from defects in NEC Electronics products, customers must incorporate sufficient safety measures in their design, such as redundancy, fire-containment and anti-failure features.
- NEC Electronics products are classified into the following three quality grades: "Standard", "Special" and
 "Specific".
 - The "Specific" quality grade applies only to NEC Electronics products developed based on a customer-designated "quality assurance program" for a specific application. The recommended applications of an NEC Electronics product depend on its quality grade, as indicated below. Customers must check the quality grade of each NEC Electronics product before using it in a particular application.
 - "Standard": Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots.
 - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).
 - "Specific": Aircraft, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems and medical equipment for life support, etc.

The quality grade of NEC Electronics products is "Standard" unless otherwise expressly specified in NEC Electronics data sheets or data books, etc. If customers wish to use NEC Electronics products in applications not intended by NEC Electronics, they must contact an NEC Electronics sales representative in advance to determine NEC Electronics' willingness to support a given application.

(Note)

- (1) "NEC Electronics" as used in this statement means NEC Electronics Corporation and also includes its majority-owned subsidiaries.
- (2) "NEC Electronics products" means any product developed or manufactured by or for NEC Electronics (as defined above).